ISO773x-Q1 EMC 性能优异的高速、增强型三通道数字隔离器

1 特性

- 符合汽车应用要求
- 具有符合 AEC-Q100 标准的下列特性：
  - 器件温度等级 1：–40°C 至 +125°C 环境工作温度范围
- 功能安全型
  - 可提供用于功能安全系统设计的文档：ISO7730-Q1, ISO7731-Q1
- 100Mbps 数据速率
- 稳健可靠的隔离栅：
  - 在 1500V_{RMS} 工作电压下预计寿命超过 100 年
  - 隔离等级高达 5000V_{RMS}
  - 浪涌能力高达 12.8kV
  - CMTI 典型值为 ±100kV/μs
- 宽电源电压范围：2.25V 至 5.5V
- 2.25V 至 5.5V 电平转换
- 默认输出*高电平* (ISO773x) 和*低电平* (ISO773xF) 选项
- 低功耗，1Mbps 时每通道的电流典型值为 1.5mA
- 低传播延迟：典型值为 11ns（5V 电源）
- 优异的电磁兼容性 (EMC)
  - 系统级 ESD、EFT 和浪涌抗扰性
  - 在整个隔离栅具有 ±8kV IEC 61000-4-2 接触放电保护
  - 低辐射
- 宽体 SOIC (DW-16) 和 QSOP (DBQ-16) 封装选项
- 安全相关认证：
  - DIN EN IEC 60747-17 (VDE 0884-17)
  - UL 1577 组件认证计划
  - IEC 61010-1、IEC 62368-1、IEC 60601-1 和 GB 4943.1 认证

2 应用

- 混合动力、电动和动力总成系统 (EV/HEV)
  - 电池管理系统 (BMS)
  - 车载充电器
  - 牵引逆变器
  - 直流/直流转换器
  - 逆变器和电机控制

3 说明

ISO773x-Q1 器件是高性能三通道数字隔离器，可提供符合 UL 1577 的 5000V_{RMS}（DW 封装）和 3000V_{RMS}（DBQ 封装）隔离额定值。

该系列包含的器件具有符合 VDE、CSA、TUV 和 CQC 标准的增强绝缘等级。

在隔离 CMOS 或 LVCMOS 数字 I/O 时，ISO773x-Q1 系列器件可提供高电磁抗扰度和低辐射，并具备低功耗特性。每条隔离通道的逻辑输入和输出缓冲器均由双电容二氧化硅 (SiO_2) 绝缘栅相隔离。该器件配有使能引脚，可用于将各自输出置于高阻态以适用于多主驱动应用中，并降低功耗。

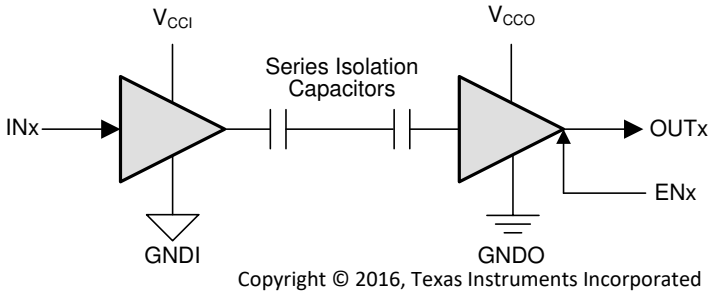
ISO7730-Q1 器件具有三条全部同向的通道，而 ISO7731-Q1 器件具有两条正向通道和一条反向通道。如果输入电源或信号丢失，不带后缀 F 的器件默认输出*高电平*，带后缀 F 的器件默认输出*低电平*。更多详细信息，请参阅*器件功能模式*部分。

该系列器件与隔离式电源结合使用，有助于防止数据总线（例如，CAN 和 LIN）或者其他电路上的噪声电流进入本地接地以及干扰或损坏敏感电路。凭借创新型芯片设计和布局技术，ISO773x-Q1 器件的电磁兼容性得到了显著增强，可轻松满足系统级 ESD、EFT、浪涌和辐射方面的合规性。ISO773x-Q1 系列器件采用 16 引脚宽体 SOIC 和 QSOP 封装。

器件信息

器件型号(1)	封装	封装尺寸（标称值）
ISO7730-Q1 ISO7731-Q1	SOIC (DW)	10.30mm × 7.50mm
	SSOP (DBQ)	4.90mm × 3.90mm

(1) 如需了解所有可用封装，请参阅数据表末尾的可订购产品附录。



V_{CCI} = 输入电源，V_{CCO} = 输出电源
GNDI = 输入接地，GNDO = 输出接地

简化版原理图

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4 Revision History

注：以前版本的页码可能与当前版本的页码不同

Changes from Revision D (October 2020) to Revision E (August 2023) — **Page**

- 将整个文档中的标准名称从“DIN V VDE V 0884-11:2017-01”更改为“DIN EN IEC 60747-17 (VDE 0884-17)” ... 1
- 通篇删除了所有标准名称中的标准版本和年份参考 ... 1
- Updated Thermal Characteristics, Safety Limiting Values, and Thermal Derating Curves to provide more accurate system-level thermal calculations ... 8
- Updated electrical and switching characteristics to match device performance ... 11
- Changed working voltage lifetime margin from: 87.5% to: 50%, minimum required insulation lifetime from: 37.5 years to: 30 years and insulation lifetime per TDDB from: 135 years to: 169 years per DIN EN IEC 60747-17 (VDE 0884-17) ... 29
- Changed 图 9-8 per DIN EN IEC 60747-17 (VDE 0884-17 ... 29

Changes from Revision C (March 2020) to Revision D (October 2020) — **Page**

- 在节 1 中添加了“功能安全”要点 ... 1

Changes from Revision B (September 2018) to Revision C (March 2020) — **Page**

- 通篇进行了编辑性和修饰性更改 ... 1
- 将“隔离栅寿命：超过 40 年”更改为“在 1500V_{RMS} 工作电压下预计寿命超过 100 年”（位于节 1） ... 1
- 在节 1 中添加了“隔离等级高达 5000V_{RMS}” ... 1
- 在节 1 中添加了“浪涌能力高达 12.8kV” ... 1

- 在节 1 中添加了“在整个隔离栅具有 ±8kV IEC 61000-4-2 接触放电保护” 1
- 将 UL 认证要点从“符合 UL 1577 的 5000V_{RMS} (DW) 和 2500V_{RMS} (DBQ) 隔离额定值”更改为“UL 1577 组件认证计划”（在节 1 中） 1
- 删除了节 1 中的“除 DBQ-16 封装器件的 CQC 认证外，所有认证均已完成”要点 1
- 更新了节 2 部分的应用列表 1
- 更新了图 3-1，以便显示每个通道的两个串联隔离电容器，而不是单个隔离电容器 1
- Added "Contact discharge per IEC 61000-4-2" specification of ±8000 V in 节 6.2 table 7
- Added the following table note to *Data rate* specification in 节 6.3 table: "100 Mbps is the maximum specified data rate, although higher data rates are possible." 7
- Changed V_{IORM} value for DW-16 package From: "1414 V_{PK}" To: "2121 V_{PK}" in 节 6.6 table 9
- Changed V_{IOWM} value for DW-16 package AC voltage From: "1000 V_{RMS}" To: "1500 V_{RMS}" and DC voltage From: "1414 V_{DC}" To: "2121 V_{DC}" in 节 6.6 table 9
- Added 'see 图 9-8' to TEST CONDITIONS of V_{IOWM} specification in 节 6.6 9
- Changed V_{IOSM} TEST CONDITIONS From: "Test method per IEC 60065" To: "Test method per IEC 62368-1" in 节 6.6 table 9
- Updated certification information in 节 6.7 table 10
- Corrected ground symbols for "Input (Devices with F suffix)" in 节 8.4.1 25
- Added 节 9.2.3.1 sub-section under 节 9.2.3 section 29
- Added '*How to use isolation to improve ESD, EFT, and Surge immunity in industrial systems*' application report to 节 12.1 section 32

Changes from Revision A (May 2017) to Revision B (June 2018) **Page**

- 通篇更改了 DIN 认证编号和认证状态 1
- 将 DBQ 封装的隔离等级从 2500V_{RMS} 更改为 3000V_{RMS} 1
- Moved the HBM and CDM values from the *Features* section to the *ESD Ratings* table 7
- Added V_{TEST} to the conditions for the maximum transient isolation voltage parameter in the *Insulation Specifications* table 9
- Changed the value for the DBQ package from 3600 VPK to 4242 V_{PK} throughout the document 9
- Changed the method b1 V_{ini} condition for apparent charge in the *Insulation Specifications* table 9

Changes from Revision * (November 2016) to Revision A (May 2017) **Page**

- Updated the *Safety-Related Certifications* table 10
- Changed the minimum CMTI from 40 to 85 in all *Electrical Characteristics* tables 11

5 Pin Configuration and Functions

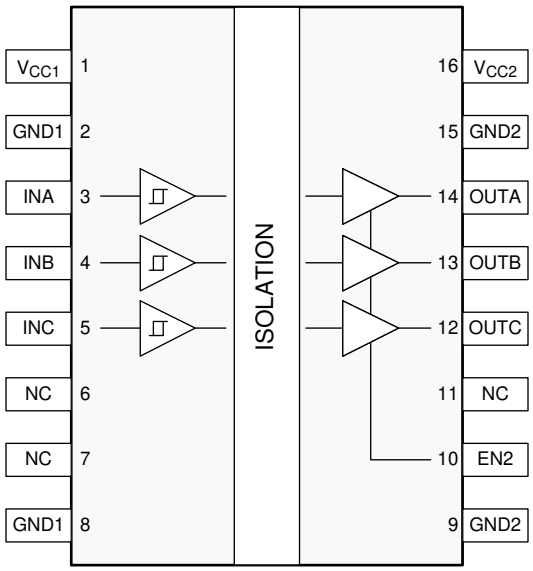


图 5-1. ISO7730-Q1 DW and DBQ Packages 16-Pin SOIC-WB and QSOP Top View

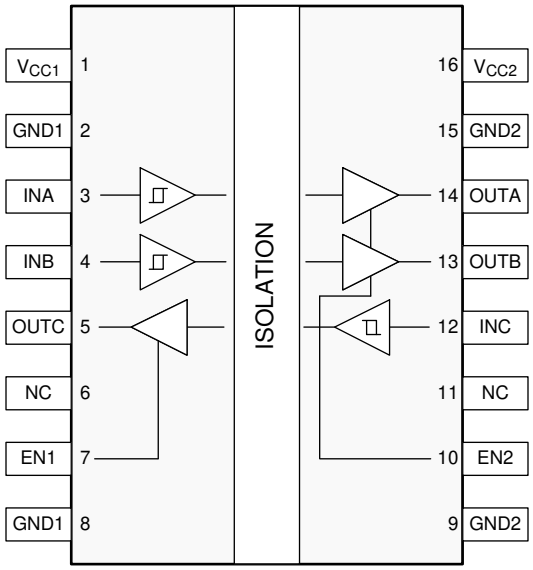


图 5-2. ISO7731-Q1 DW and DBQ Packages 16-Pin SOIC-WB and QSOP Top View

表 5-1. Pin Functions

PIN			I/O	DESCRIPTION
NAME	NO.			
	ISO7730-Q1	ISO7731-Q1		
EN1	—	7	I	Output enable 1. Output pins on side 1 are enabled when EN1 is high or open and in high-impedance state when EN1 is low.
EN2	10	10	I	Output enable 2. Output pins on side 2 are enabled when EN2 is high or open and in high-impedance state when EN2 is low.
GND1	2, 8	2, 8	—	Ground connection for V_{CC1}
GND2	9, 15	9, 15	—	Ground connection for V_{CC2}
INA	3	3	I	Input, channel A
INB	4	4	I	Input, channel B
INC	5	12	I	Input, channel C
NC	6, 7, 11	6, 11	—	Not connected
OUTA	14	14	O	Output, channel A
OUTB	13	13	O	Output, channel B
OUTC	12	5	O	Output, channel C
V_{CC1}	1	1	—	Power supply, V_{CC1}
V_{CC2}	16	16	—	Power supply, V_{CC2}

6 Specifications

6.1 Absolute Maximum Ratings

See (1)

		MIN	MAX	UNIT
V_{CC1}, V_{CC2}	Supply voltage(2)	–0.5	6	V
V	Voltage at INx, OUTx, ENx	–0.5	V_{CCX} + 0.5(3)	V
I_O	Output current	–15	15	mA
T_J	Junction temperature		150	°C
T_{stg}	Storage temperature	–65	150	°C

(1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
(2) All voltage values except differential I/O bus voltages are with respect to the local ground terminal (GND1 or GND2) and are peak voltage values.
(3) Maximum voltage must not exceed 6 V.

6.2 ESD Ratings

			VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human-body model (HBM), per AEC Q100-002(1) HBM ESD Classification Level 3A	±6000	V
		Charged-device model (CDM), per AEC Q100-011 CDM ESD Classification Level C6	±1500	
		Contact discharge per IEC 61000-4-2; Isolation barrier withstand test(2) (3)	±8000	

(1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.
(2) IEC ESD strike is applied across the barrier with all pins on each side tied together creating a two-terminal device.
(3) Testing is carried out in air or oil to determine the intrinsic contact discharge capability of the device.

6.3 Recommended Operating Conditions

			MIN	NOM	MAX	UNIT
V_{CC1}, V_{CC2}	Supply voltage		2.25		5.5	V
$V_{CC(UVLO+)}$	UVLO threshold when supply voltage is rising			2	2.25	V
$V_{CC(UVLO-)}$	UVLO threshold when supply voltage is falling		1.7	1.8		V
$V_{HYS(UVLO)}$	Supply voltage UVLO hysteresis		100	200		mV
I_{OH}	High-level output current	V_{CCO} (1) = 5 V	–4			mA
		V_{CCO} = 3.3 V	–2			
		V_{CCO} = 2.5 V	–1			
I_{OL}	Low-level output current	V_{CCO} = 5 V			4	mA
		V_{CCO} = 3.3 V			2	
		V_{CCO} = 2.5 V			1	
V_{IH}	High-level input voltage		0.7 × V_{CCI} (1)		V_{CCI}	V
V_{IL}	Low-level input voltage		0		0.3 × V_{CCI}	V
DR(2)	Data rate(2)		0		100	Mbps
T_A	Ambient temperature		-40	25	125	°C

(1) V_{CCI} = Input-side V_{CC}; V_{CCO} = Output-side V_{CC}.
(2) 100 Mbps is the maximum specified data rate, although higher data rates are possible.

6.4 Thermal Information

THERMAL METRIC[1]		ISO773x-Q1		UNIT
		DW (SOIC)	DBQ (QSOP)	
		16 Pins	16 Pins	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	81.4	109	°C/W
$R_{\theta JC(top)}$	Junction-to-case(top) thermal resistance	44.9	46.8	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	45.9	60.6	°C/W
ψ_{JT}	Junction-to-top characterization parameter	28.1	35.9	°C/W
ψ_{JB}	Junction-to-board characterization parameter	45.5	60	°C/W
$R_{\theta JC(bottom)}$	Junction-to-case(bottom) thermal resistance	—	—	°C/W

(1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report.

6.5 Power Ratings

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
ISO7730-Q1						
P_D	Maximum power dissipation	V_{CC1} = V_{CC2} = 5.5 V, T_J = 150°C, C_L = 15 pF, input a 50-MHz 50% duty cycle square wave			150	mW
P_{D1}	Maximum power dissipation by side-1				25	mW
P_{D2}	Maximum power dissipation by side-2				125	mW
ISO7731-Q1						
P_D	Maximum power dissipation	V_{CC1} = V_{CC2} = 5.5 V, T_J = 150°C, C_L = 15 pF, input a 50-MHz 50% duty cycle square wave			150	mW
P_{D1}	Maximum power dissipation by side-1				50	mW
P_{D2}	Maximum power dissipation by side-2				100	mW

6.6 Insulation Specifications

PARAMETER		TEST CONDITIONS	SPECIFICATION		UNIT
			DW-16	DBQ-16	
CLR	External clearance (1)	Shortest terminal-to-terminal distance through air	>8	>3.7	mm
CPG	External creepage (1)	Shortest terminal-to-terminal distance across the package surface	>8	>3.7	mm
DTI	Distance through the insulation	Minimum internal gap (internal clearance)	>21	>21	µm
CTI	Comparative tracking index	DIN EN 60112 (VDE 0303-11); IEC 60112; UL 746A	>600	>600	V
	Material group	According to IEC 60664-1	I	I	
	Overvoltage category per IEC 60664-1	Rated mains voltage ≤ 150 V_{RMS}	I – IV	I – IV	
		Rated mains voltage ≤ 300 V_{RMS}	I – IV	I – III	
		Rated mains voltage ≤ 600 V_{RMS}	I – IV	n/a	
		Rated mains voltage ≤ 1000 V_{RMS}	I – III	n/a	
DIN VDE V 0884-11:2017-01(2)					
V_{IORM}	Maximum repetitive peak isolation voltage	AC voltage (bipolar)	2121	566	V_{PK}
V_{IOWM}	Maximum working isolation voltage	AC voltage; Time dependent dielectric breakdown (TDDB) Test; See 图 9-8	1500	400	V_{RMS}
		DC Voltage	2121	566	V_{DC}
V_{IOTM}	Maximum transient isolation voltage	V_{TEST} = V_{IOTM}, t = 60 s (qualification); V_{TEST} = 1.2 × V_{IOTM}, t = 1 s (100% production)	8000	4242	V_{PK}
V_{IOSM}	Maximum surge isolation voltage (3)	Test method per IEC 62368-1; 1.2/50 µs waveform, V_{TEST} = 1.6 × V_{IOSM} (qualification)	8000	4000	V_{PK}
q_{pd}	Apparent charge(4)	Method a, After Input/Output safety test subgroup 2/3, V_{ini} = V_{IOTM}, t_{ini} = 60 s; $V_{pd(m)}$ = 1.2 × V_{IORM}, t_m = 10 s	≤5	≤5	pC
		Method a, After environmental tests subgroup 1, V_{ini} = V_{IOTM}, t_{ini} = 60 s; $V_{pd(m)}$ = 1.6 × V_{IORM}, t_m = 10 s	≤5	≤5	
		Method b1; At routine test (100% production) and preconditioning (type test) V_{ini} = 1.2 × V_{IOTM}, t_{ini} = 1 s; $V_{pd(m)}$ = 1.875 × V_{IORM}, t_m = 1 s	≤5	≤5	
C_{IO}	Barrier capacitance, input to output(5)	V_{IO} = 0.4 x sin (2 π ft), f = 1 MHz	~0.7	~0.7	pF
R_{IO}	Isolation resistance(5)	V_{IO} = 500 V, T_A = 25°C	$>10^{12}$	$>10^{12}$	Ω
		V_{IO} = 500 V, 100°C ≤ T_A ≤ 125°C	$>10^{11}$	$>10^{11}$	
		V_{IO} = 500 V at T_S = 150°C	$>10^9$	$>10^9$	
	Pollution degree		2	2	
	Climatic category		55/125/21	55/125/21	
UL 1577					
V_{ISO}	Withstanding isolation voltage	V_{TEST} = V_{ISO} , t = 60 s (qualification), V_{TEST} = 1.2 × V_{ISO} , t = 1 s (100% production)	5000	3000	V_{RMS}

(1) Creepage and clearance requirements should be applied according to the specific equipment isolation standards of an application. Care should be taken to maintain the creepage and clearance distance of a board design to ensure that the mounting pads of the isolator on the printed-circuit board do not reduce this distance. Creepage and clearance on a printed-circuit board become equal in certain cases. Techniques such as inserting grooves and/or ribs on a printed circuit board are used to help increase these specifications.
(2) This coupler is suitable for *safe electrical insulation* only within the safety ratings. Compliance with the safety ratings shall be ensured by means of suitable protective circuits.
(3) Testing is carried out in air or oil to determine the intrinsic surge immunity of the isolation barrier.
(4) Apparent charge is electrical discharge caused by a partial discharge (pd).
(5) All pins on each side of the barrier tied together creating a two-terminal device.

6.7 Safety-Related Certifications

VDE	CSA	UL	CQC	TUV
Certified according to DIN VDE V 0884-11:2017-01	Certified according to IEC 60950-1, IEC 62368-1 and IEC 60601-1	Certified according to UL 1577 Component Recognition Program	Certified according to GB 4943.1-2011	Certified according to EN 61010-1:2010/A1:2019, EN 60950-1:2006/A2:2013 and EN 62368-1:2014
Maximum transient isolation voltage, 8000 V_{PK} (DW-16) and 4242 V_{PK} (DBQ-16); Maximum repetitive peak isolation voltage, 2121 V_{PK} (DW-16, Reinforced) and 566 V_{PK} (DBQ-16); Maximum surge isolation voltage, 8000 V_{PK} (DW-16) and 4000 V_{PK} (DBQ-16)	Reinforced insulation per CSA 60950-1-07+A1+A2, IEC 60950-1 2nd Ed.+A1+A2, CSA 62368-1-14 and IEC 62368-1:2014, 800 V_{RMS} (DW-16) max working voltage (pollution degree 2, material group I); 2 MOPP (Means of Patient Protection) per CSA 60601-1:14 and IEC 60601-1 Ed. 3.1, 250 V_{RMS} (DW-16) max working voltage	**DW-16:** Single protection, 5000 V_{RMS}; **DBQ-16:** Single protection, 3000 V_{RMS}	**DW-16:** Reinforced Insulation, Altitude ≤ 5000 m, Tropical Climate, 700 V_{RMS} maximum working voltage; **DBQ-16:** Basic Insulation, Altitude ≤ 5000 m, Tropical Climate, 400 V_{RMS} maximum working voltage	5000 V_{RMS} (DW-16) and 3000 V_{RMS} (DBQ-16) Reinforced insulation per EN 61010-1:2010/A1:2019 up to working voltage of 600 V_{RMS} (DW-16) and 300 V_{RMS} (DBQ-16) 5000 V_{RMS} (DW-16) and 3000 V_{RMS} (DBQ-16) Reinforced insulation per EN 60950-1:2006/A2:2013 and EN 62368-1:2014 up to working voltage of 800 V_{RMS} (DW -16) and 370 V_{RMS} (DBQ-16)
Certificate number: 40040142	Master contract number: 220991	File number: E181974	Certificate numbers: CQC15001121716 (DW-16) CQC18001199097 (DBQ-16)	Client ID number: 77311

6.8 Safety Limiting Values

Safety limiting(1) intends to minimize potential damage to the isolation barrier upon failure of input or output circuitry. A failure of the I/O can allow low resistance to ground or the supply and, without current limiting, dissipate sufficient power to overheat the die and damage the isolation barrier potentially leading to secondary system failures.

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
DW-16 PACKAGE						
I_S	Safety input, output, or supply current	$R_{\theta JA}$ = 81.4 °C/W, V_I = 5.5 V, T_J = 150°C, T_A = 25°C, see 图 6-1			279	mA
		$R_{\theta JA}$ = 81.4 °C/W, V_I = 3.6 V, T_J = 150°C, T_A = 25°C, see 图 6-1			427	
		$R_{\theta JA}$ = 81.4 °C/W, V_I = 2.75 V, T_J = 150°C, T_A = 25°C, see 图 6-1			558	
P_S	Safety input, output, or total power	$R_{\theta JA}$ = 81.4 °C/W, T_J = 150°C, T_A = 25°C, see 图 6-3			1536	mW
T_S	Maximum safety temperature				150	°C
DBQ-16 PACKAGE						
I_S	Safety input, output, or supply current	$R_{\theta JA}$ = 109.0°C/W, V_I = 5.5 V, T_J = 150°C, T_A = 25°C, see 图 6-2			209	mA
		$R_{\theta JA}$ = 109.0 °C/W, V_I = 3.6 V, T_J = 150°C, T_A = 25°C, see 图 6-2			319	
		$R_{\theta JA}$ = 109.0°C/W, V_I = 2.75 V, T_J = 150°C, T_A = 25°C, see 图 6-2			417	
P_S	Safety input, output, or total power	$R_{\theta JA}$ = 109.0°C/W, T_J = 150°C, T_A = 25°C, see 图 6-4			1147	mW
T_S	Maximum safety temperature				150	°C

(1) The maximum safety temperature is the maximum junction temperature specified for the device. The power dissipation and junction-to-air thermal impedance of the device installed in the application hardware determines the junction temperature. The assumed junction-to-air thermal resistance in the *节 6.4* is that of a device installed on a High-K test board for leaded surface mount packages. The power is the recommended maximum input voltage times the current. The junction temperature is then the ambient temperature plus the power times the junction-to-air thermal resistance.

6.9 Electrical Characteristics—5-V Supply

V_{CC1} = V_{CC2} = 5 V ±10% (over recommended operating conditions unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{OH}	High-level output voltage	I_{OH} = –4 mA; see 图 7-1	V_{CCO} (1) – 0.4	4.8		V
V_{OL}	Low-level output voltage	I_{OL} = 4 mA; see 图 7-1		0.2	0.4	V
$V_{IT+(IN)}$	Rising input voltage threshold			0.6 × V_{CCI}	0.7 × V_{CCI}	V
$V_{IT-(IN)}$	Falling input voltage threshold		0.3 × V_{CCI}	0.4 × V_{CCI}		V
$V_{I(HYS)}$	Input threshold voltage hysteresis		0.1 × V_{CCI}	0.2 × V_{CCI}		V
I_{IH}	High-level input current	V_{IH} = V_{CCI} (1) at INx or ENx			10	µA
I_{IL}	Low-level input current	V_{IL} = 0 V at INx or ENx	–10			µA
CMTI	Common-mode transient immunity	V_I = V_{CCI} or 0 V, V_{CM} = 1200 V; see 图 7-4	85	100		kV/µs
C_I	Input Capacitance(2)	V_I = V_{CC}/ 2 + 0.4×sin(2πft), f = 1 MHz, V_{CC} = 5 V		2		pF

(1) V_{CCI} = Input-side V_{CC}; V_{CCO} = Output-side V_{CC}.
(2) Measured from input pin to ground.

6.10 Supply Current Characteristics—5-V Supply

V_{CC1} = V_{CC2} = 5 V ±10% (over recommended operating conditions unless otherwise noted)

PARAMETER	TEST CONDITIONS		SUPPLY CURRENT	MIN	TYP	MAX	UNIT
ISO7730-Q1							
Supply current - disable	EN2 = 0 V; V_I = V_{CC1} (ISO7730-Q1); V_I = 0 V (ISO7730-Q1 with F suffix)		I_{CC1}		1	1.4	mA
			I_{CC2}		0.3	0.4	mA
	EN2 = 0 V; V_I = 0 V (ISO7730-Q1); V_I = V_{CC1} (ISO7730-Q1 with F suffix)		I_{CC1}		4.3	6	mA
			I_{CC2}		0.3	0.4	mA
Supply current - DC signal	EN2 = V_{CC2}; V_I = V_{CC1} (ISO7730-Q1); V_I = 0 V (ISO7730-Q1 with F suffix)		I_{CC1}		1	1.4	mA
			I_{CC2}		1.6	2.5	mA
	EN2 = V_{CC2}; V_I = 0 V (ISO7730-Q1); V_I = V_{CC1} (ISO7730-Q1 with F suffix)		I_{CC1}		4.3	6	mA
			I_{CC2}		1.8	2.7	mA
Supply current - AC signal	EN2 = V_{CCI}; All channels switching with square wave clock input; C_L = 15 pF	1 Mbps	I_{CC1}		2.6	3.7	mA
			I_{CC2}		1.9	2.8	mA
		10 Mbps	I_{CC1}		2.7	3.8	mA
			I_{CC2}		3.3	4.5	mA
		100 Mbps	I_{CC1}		3.6	4.6	mA
			I_{CC2}		17.5	21	mA
ISO7731-Q1							
Supply current - disable	EN1 = EN2 = 0 V; V_I = V_{CCI} (1) (ISO7731-Q1); V_I = 0 V (ISO7731-Q1 with F suffix)		I_{CC1}		0.8	1.2	mA
			I_{CC2}		0.7	1	mA
	EN1 = EN2 = 0 V; V_I = 0 V (ISO7731-Q1); V_I = V_{CCI} (ISO7731-Q1 with F suffix)		I_{CC1}		3	4.3	mA
			I_{CC2}		1.8	2.6	mA
Supply current - DC signal	EN1 = EN2 = V_{CCI}; V_I = V_{CCI} (ISO7731-Q1); V_I = 0 V (ISO7731-Q1 with F suffix)		I_{CC1}		1.3	1.7	mA
			I_{CC2}		1.6	2.2	mA
	EN1 = EN2 = V_{CCI}; V_I = 0 V (ISO7731-Q1); V_I = V_{CCI} (ISO7731-Q1 with F suffix)		I_{CC1}		3.5	5	mA
			I_{CC2}		2.8	4.1	mA

V_{CC1} = V_{CC2} = 5 V ±10% (over recommended operating conditions unless otherwise noted)

PARAMETER	TEST CONDITIONS		SUPPLY CURRENT	MIN	TYP	MAX	UNIT
Supply current - AC signal	EN1 = EN2 = V_{CCI}; All channels switching with square wave clock input; C_L = 15 pF	1 Mbps	I_{CC1}		2.7	3.4	mA
			I_{CC2}		2.3	3.3	mA
		10 Mbps	I_{CC1}		3	4	mA
			I_{CC2}		3.3	4.4	mA
		100 Mbps	I_{CC1}		8.5	11	mA
			I_{CC2}		13.1	16	mA

(1) V_{CCI} = Input-side V_{CC}

6.11 Electrical Characteristics—3.3-V Supply

V_{CC1} = V_{CC2} = 3.3 V ±10% (over recommended operating conditions unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{OH}	High-level output voltage	I_{OH} = – 2 mA; see 图 7-1	V_{CCO} (1) – 0.3	3.2		V
V_{OL}	Low-level output voltage	I_{OL} = 2 mA; see 图 7-1		0.1	0.3	V
$V_{IT+(IN)}$	Rising input voltage threshold			0.6 × V_{CCI}	0.7 × V_{CCI}	V
$V_{IT-(IN)}$	Falling input voltage threshold		0.3 × V_{CCI}	0.4 × V_{CCI}		V
$V_{I(HYS)}$	Input threshold voltage hysteresis		0.1 × V_{CCI}	0.2 × V_{CCI}		V
I_{IH}	High-level input current	V_{IH} = V_{CCI} (1) at INx or ENx			10	μA
I_{IL}	Low-level input current	V_{IL} = 0 V at INx or ENx	– 10			μA
CMTI	Common-mode transient immunity	V_I = V_{CCI} or 0 V, V_{CM} = 1200 V; see 图 7-4	85	100		kV/μs

(1) V_{CCI} = Input-side V_{CC}; V_{CCO} = Output-side V_{CC}.

6.12 Supply Current Characteristics—3.3-V Supply

V_{CC1} = V_{CC2} = 3.3 V ±10% (over recommended operating conditions unless otherwise noted)

PARAMETER	TEST CONDITIONS		SUPPLY CURRENT	MIN	TYP	MAX	UNIT
ISO7730-Q1							
Supply current - disable	EN2 = 0 V; V_I = V_{CC1} (ISO7730-Q1); V_I = 0 V (ISO7730-Q1 with F suffix)		I_{CC1}		1	1.4	mA
			I_{CC2}		0.3	0.4	mA
	EN2 = 0 V; V_I = 0 V (ISO7730-Q1); V_I = V_{CC1} (ISO7730-Q1 with F suffix)		I_{CC1}		4.3	6	mA
			I_{CC2}		0.3	0.4	mA
Supply current - DC signal	EN2 = V_{CC2}; V_I = V_{CC1} (ISO7730-Q1); V_I = 0 V (ISO7730-Q1 with F suffix)		I_{CC1}		1	1.4	mA
			I_{CC2}		1.6	2.5	mA
	EN2 = V_{CC2}; V_I = 0 V (ISO7730-Q1); V_I = V_{CC1} (ISO7730-Q1 with F suffix)		I_{CC1}		4.3	6	mA
			I_{CC2}		1.8	2.7	mA
Supply current - AC signal	EN2 = V_{CCI}; All channels switching with square wave clock input; C_L = 15 pF	1 Mbps	I_{CC1}		2.6	3.7	mA
			I_{CC2}		1.8	2.8	mA
		10 Mbps	I_{CC1}		2.7	3.8	mA
			I_{CC2}		2.8	3.9	mA
		100 Mbps	I_{CC1}		3.3	4.3	mA
			I_{CC2}		13	17	mA
ISO7731-Q1							
Supply current - disable	EN1 = EN2 = 0 V; V_I = V_{CCI} (1) (ISO7731-Q1); V_I = 0 V (ISO7731-Q1 with F suffix)		I_{CC1}		0.8	1.2	mA
			I_{CC2}		0.7	1	mA
	EN1 = EN2 = 0 V; V_I = 0 V (ISO7731-Q1); V_I = V_{CCI} (ISO7731-Q1 with F suffix)		I_{CC1}		3	4.3	mA
			I_{CC2}		1.8	2.6	mA
Supply current - DC signal	EN1 = EN2 = V_{CCI}; V_I = V_{CCI} (ISO7731-Q1); V_I = 0 V (ISO7731-Q1 with F suffix)		I_{CC1}		1.3	1.7	mA
			I_{CC2}		1.6	2.2	mA
	EN1 = EN2 = V_{CCI}; V_I = 0 V (ISO7731-Q1); V_I = V_{CCI} (ISO7731-Q1 with F suffix)		I_{CC1}		3.5	5	mA
			I_{CC2}		2.8	4.1	mA
Supply current - AC signal	EN1 = EN2 = V_{CCI}; All channels switching with square wave clock input; C_L = 15 pF	1 Mbps	I_{CC1}		2.4	3.4	mA
			I_{CC2}		2.2	3.3	mA
		10 Mbps	I_{CC1}		2.8	3.8	mA
			I_{CC2}		2.9	4	mA
		100 Mbps	I_{CC1}		6.7	8.5	mA
			I_{CC2}		10	12.5	mA

(1) V_{CCI} = Input-side V_{CC}

6.13 Electrical Characteristics—2.5-V Supply

V_{CC1} = V_{CC2} = 2.5 V ±10% (over recommended operating conditions unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{OH}	High-level output voltage	I_{OH} = – 1 mA; see 图 7-1	V_{CCO} (1) – 0.2	2.45		V
V_{OL}	Low-level output voltage	I_{OL} = 1 mA; see 图 7-1		0.05	0.2	V
$V_{IT+(IN)}$	Rising input voltage threshold			0.6 × V_{CCI}	0.7 × V_{CCI}	V
$V_{IT-(IN)}$	Falling input voltage threshold		0.3 × V_{CCI}	0.4 × V_{CCI}		V
$V_{I(HYS)}$	Input threshold voltage hysteresis		0.1 × V_{CCI}	0.2 × V_{CCI}		V
I_{IH}	High-level input current	V_{IH} = V_{CCI} (1) at INx or ENx			10	μA
I_{IL}	Low-level input current	V_{IL} = 0 V at INx or ENx	– 10			μA
CMTI	Common-mode transient immunity	V_I = V_{CCI} or 0 V, V_{CM} = 1200 V; see 图 7-4	85	100		kV/μs

(1) V_{CCI} = Input-side V_{CC}; V_{CCO} = Output-side V_{CC}.

6.14 Supply Current Characteristics—2.5-V Supply

V_{CC1} = V_{CC2} = 2.5 V ±10% (over recommended operating conditions unless otherwise noted)

PARAMETER	TEST CONDITIONS		SUPPLY CURRENT	MIN	TYP	MAX	UNIT
ISO7730-Q1							
Supply current - disable	EN2 = 0 V; V_I = V_{CC1} (ISO7730-Q1); V_I = 0 V (ISO7730-Q1 with F suffix)		I_{CC1}		1	1.4	mA
			I_{CC2}		0.3	0.4	mA
	EN2 = 0 V; V_I = 0 V (ISO7730-Q1); V_I = V_{CC1} (ISO7730-Q1 with F suffix)		I_{CC1}		4.3	6	mA
			I_{CC2}		0.3	0.4	mA
Supply current - DC signal	EN2 = V_{CC2}; V_I = V_{CC1} (ISO7730-Q1); V_I = 0 V (ISO7730-Q1 with F suffix)		I_{CC1}		1	1.4	mA
			I_{CC2}		1.6	2.5	mA
	EN2 = V_{CC2}; V_I = 0 V (ISO7730-Q1); V_I = V_{CC1} (ISO7730-Q1 with F suffix)		I_{CC1}		4.3	6	mA
			I_{CC2}		1.8	2.7	mA
Supply current - AC signal	EN2 = V_{CC2}; All channels switching with square wave clock input; C_L = 15 pF	1 Mbps	I_{CC1}		2.6	3.7	mA
			I_{CC2}		1.8	2.7	mA
		10 Mbps	I_{CC1}		2.6	3.8	mA
			I_{CC2}		2.5	3.6	mA
		100 Mbps	I_{CC1}		3.1	4.2	mA
			I_{CC2}		10.2	14	mA
ISO7731-Q1							
Supply current - disable	EN1 = EN2 = 0 V; V_I = V_{CCI} (1) (ISO7731-Q1); V_I = 0 V (ISO7731-Q1 with F suffix)		I_{CC1}		0.8	1.2	mA
			I_{CC2}		0.7	1	mA
	EN1 = EN2 = 0 V; V_I = 0 V (ISO7731-Q1); V_I = V_{CCI} (ISO7731-Q1 with F suffix)		I_{CC1}		3	4.3	mA
			I_{CC2}		1.8	2.6	mA
Supply current - DC signal	EN1 = EN2 = V_{CCI}; V_I = V_{CCI} (ISO7731-Q1); V_I = 0 V (ISO7731-Q1 with F suffix)		I_{CC1}		1.3	1.7	mA
			I_{CC2}		1.6	2.2	mA
	EN1 = EN2 = V_{CCI}; V_I = 0 V (ISO7731-Q1); V_I = V_{CCI} (ISO7731-Q1 with F suffix)		I_{CC1}		3.5	5	mA
			I_{CC2}		2.8	4.1	mA
Supply current - AC signal	EN1 = EN2 = V_{CCI}; All channels switching with square wave clock input; C_L = 15 pF	1 Mbps	I_{CC1}		2.4	3.4	mA
			I_{CC2}		2.2	3.2	mA
		10 Mbps	I_{CC1}		2.7	3.7	mA
			I_{CC2}		2.7	3.8	mA
		100 Mbps	I_{CC1}		5.6	7	mA
			I_{CC2}		8	10	mA

(1) V_{CCI} = Input-side V_{CC}

6.15 Switching Characteristics—5-V Supply

V_{CC1} = V_{CC2} = 5 V ±10% (over recommended operating conditions unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{PLH}, t_{PHL}	Propagation delay time	See 图 7-1	6	11	16	ns
PWD	Pulse width distortion(1) $\lvert t_{PHL} - t_{PLH} \rvert$			0.6	4.9	ns
$t_{sk(o)}$	Channel-to-channel output skew time(2)	Same-direction channels			4	ns
$t_{sk(pp)}$	Part-to-part skew time(3)				4.5	ns
t_r	Output signal rise time	See 图 7-1		1.3	3.9	ns
t_f	Output signal fall time			1.4	3.9	ns
t_{PHZ}	Disable propagation delay, high-to-high impedance output	See 图 7-2		8	20	ns
t_{PLZ}	Disable propagation delay, low-to-high impedance output			8	20	ns
t_{PZH}	Enable propagation delay, high impedance-to-high output for ISO773x-Q1			7	20	ns
	Enable propagation delay, high impedance-to-high output for ISO773x-Q1 with F suffix			3	8.5	µs
t_{PZL}	Enable propagation delay, high impedance-to-low output for ISO773x-Q1			3	8.5	µs
	Enable propagation delay, high impedance-to-low output for ISO773x-Q1 with F suffix			7	20	ns
t_{DO}	Default output delay time from input power loss	Measured from the time V_{CC} goes below 1.7 V. See 图 7-3		0.1	0.3	µs
t_{ie}	Time interval error	2^{16} – 1 PRBS data at 100 Mbps		0.6		ns

(1) Also known as pulse skew.
(2) $t_{sk(o)}$ is the skew between outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical loads.
(3) $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any terminals of different devices switching in the same direction while operating at identical supply voltages, temperature, input signals and loads.

6.16 Switching Characteristics—3.3-V Supply

V_{CC1} = V_{CC2} = 3.3 V ±10% (over recommended operating conditions unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{PLH}, t_{PHL}	Propagation delay time	See 图 7-1	6	11	16	ns
PWD	Pulse width distortion(1) $\lvert t_{PHL} - t_{PLH} \rvert$			0.1	5	ns
$t_{sk(o)}$	Channel-to-channel output skew time(2)	Same-direction channels			4.1	ns
$t_{sk(pp)}$	Part-to-part skew time(3)				4.5	ns
t_r	Output signal rise time	See 图 7-1		1.3	3	ns
t_f	Output signal fall time			1.3	3	ns
t_{PHZ}	Disable propagation delay, high-to-high impedance output	See 图 7-2		17	30	ns
t_{PLZ}	Disable propagation delay, low-to-high impedance output			17	30	ns
t_{PZH}	Enable propagation delay, high impedance-to-high output for ISO773x-Q1			17	30	ns
	Enable propagation delay, high impedance-to-high output for ISO773x-Q1 with F suffix			3.2	8.5	µs
t_{PZL}	Enable propagation delay, high impedance-to-low output for ISO773x-Q1			3.2	8.5	µs
	Enable propagation delay, high impedance-to-low output for ISO773x-Q1 with F suffix			17	30	ns
t_{DO}	Default output delay time from input power loss	Measured from the time V_{CC} goes below 1.7 V. See 图 7-3		0.1	0.3	µs
t_{ie}	Time interval error	2^{16} – 1 PRBS data at 100 Mbps		0.6		ns

(1) Also known as Pulse Skew.
(2) $t_{sk(o)}$ is the skew between outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical loads.
(3) $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any terminals of different devices switching in the same direction while operating at identical supply voltages, temperature, input signals and loads.

6.17 Switching Characteristics—2.5-V Supply

V_{CC1} = V_{CC2} = 2.5 V ±10% (over recommended operating conditions unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{PLH}, t_{PHL}	Propagation delay time	See 图 7-1	7.5	12	18.5	ns
PWD	Pulse width distortion(1) $\lvert t_{PHL} - t_{PLH} \rvert$			0.2	5.1	ns
$t_{sk(o)}$	Channel-to-channel output skew time(2)	Same-direction Channels			4.1	ns
$t_{sk(pp)}$	Part-to-part skew time(3)				4.6	ns
t_r	Output signal rise time	See 图 7-1		1	3.5	ns
t_f	Output signal fall time			1	3.5	ns
t_{PHZ}	Disable propagation delay, high-to-high impedance output	See 图 7-2		22	40	ns
t_{PLZ}	Disable propagation delay, low-to-high impedance output			22	40	ns
t_{PZH}	Enable propagation delay, high impedance-to-high output for ISO773x-Q1			18	40	ns
	Enable propagation delay, high impedance-to-high output for ISO773x-Q1 with F suffix			3.3	8.5	µs
t_{PZL}	Enable propagation delay, high impedance-to-low output for ISO773x-Q1			3.3	8.5	µs
	Enable propagation delay, high impedance-to-low output for ISO773x-Q1 with F suffix			18	40	ns
t_{DO}	Default output delay time from input power loss	Measured from the time V_{CC} goes below 1.7 V. See 图 7-3		0.1	0.3	µs
t_{ie}	Time interval error	2^{16} – 1 PRBS data at 100 Mbps		0.6		ns

(1) Also known as pulse skew.
(2) $t_{sk(o)}$ is the skew between outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical loads.
(3) $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any terminals of different devices switching in the same direction while operating at identical supply voltages, temperature, input signals and loads.

6.18 Insulation Characteristics Curves

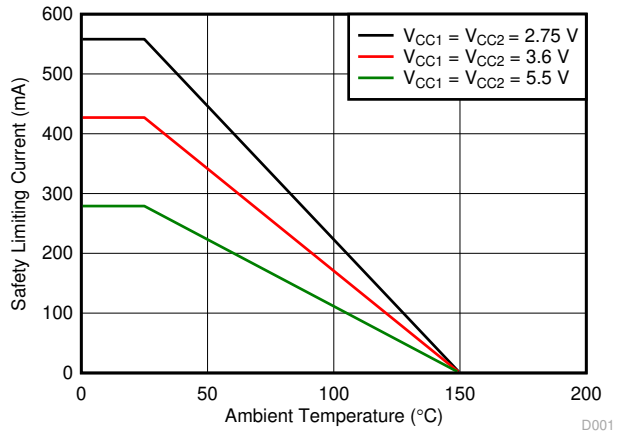


图 6-1. Thermal Derating Curve for Safety Limiting Current per VDE for DW-16 Package

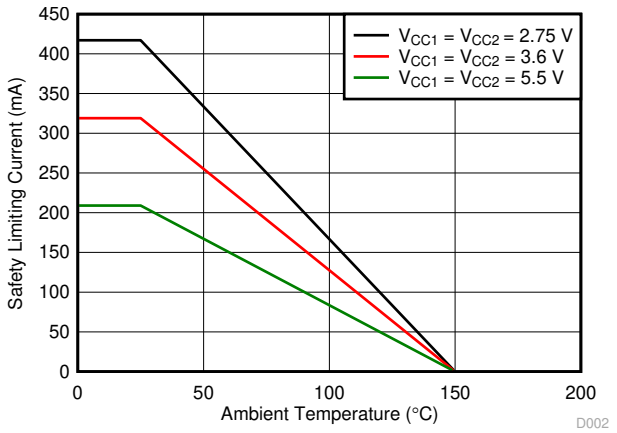


图 6-2. Thermal Derating Curve for Safety Limiting Current per VDE for DBQ-16 Package

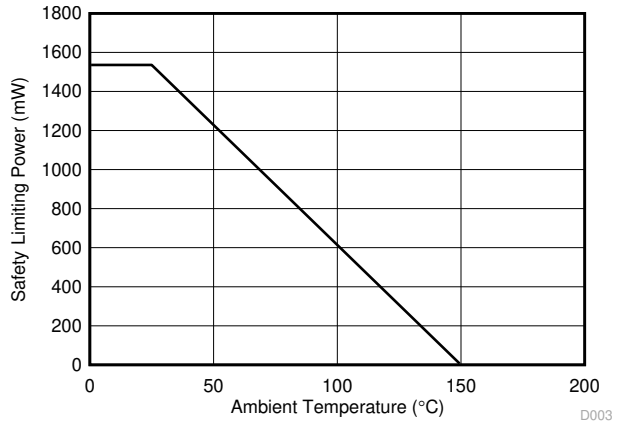


图 6-3. Thermal Derating Curve for Safety Limiting Power per VDE for DW-16 Package

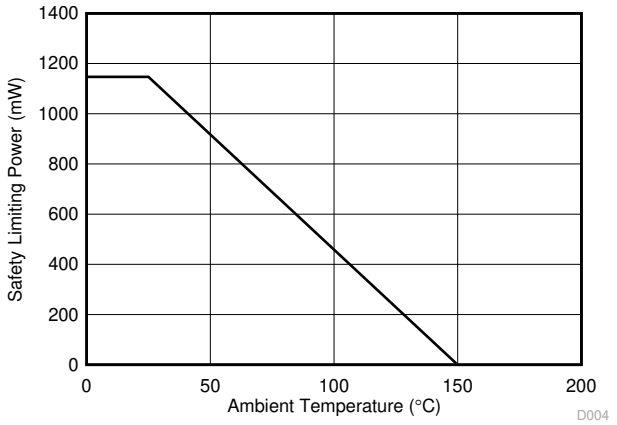


图 6-4. Thermal Derating Curve for Safety Limiting Power per VDE for DBQ-16 Package

6.19 Typical Characteristics

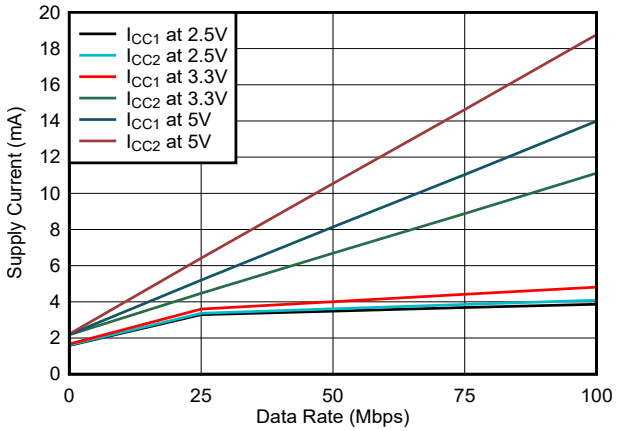


图 6-5. ISO7730-Q1 Supply Current vs Data Rate (With 15-pF Load)

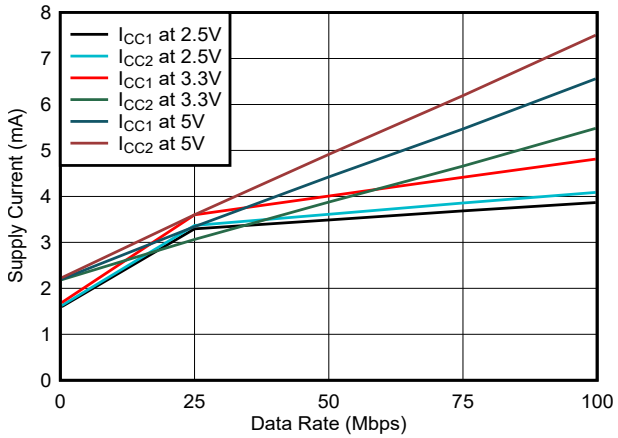


图 6-6. ISO7730-Q1 Supply Current vs Data Rate (With No Load)

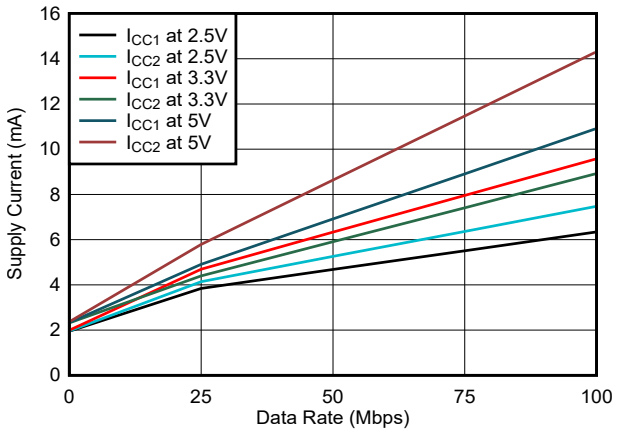


图 6-7. ISO7731-Q1 Supply Current vs Data Rate (With 15-pF Load)

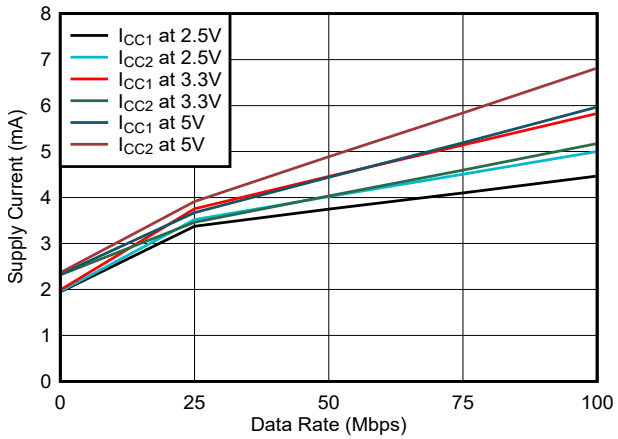


图 6-8. ISO7731-Q1 Supply Current vs Data Rate (With No Load)

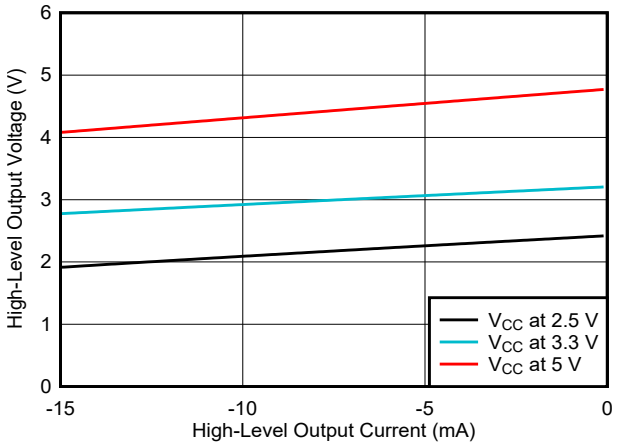


图 6-9. High-Level Output Voltage vs High-level Output Current

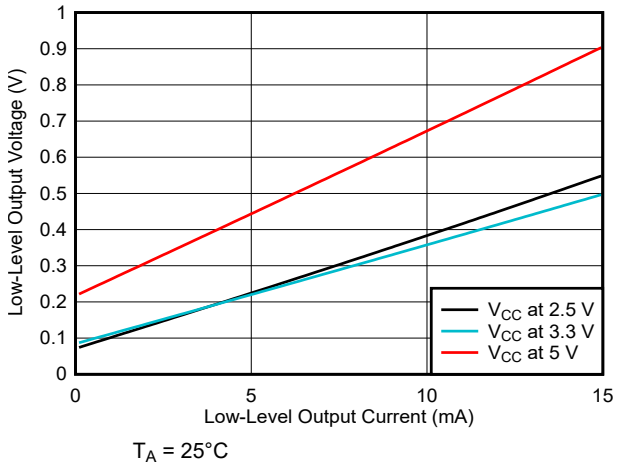


图 6-10. Low-Level Output Voltage vs Low-Level Output Current

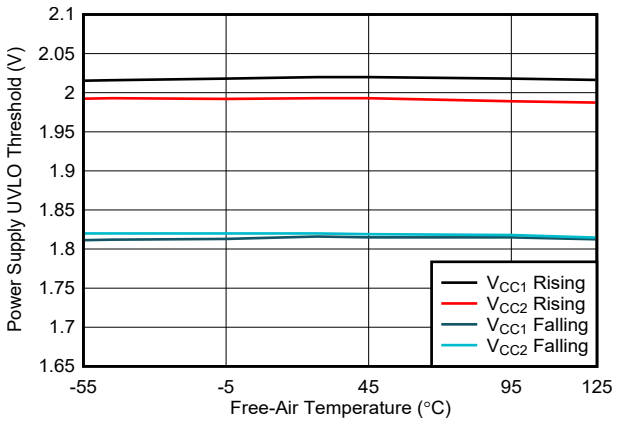


图 6-11. Power Supply Undervoltage Threshold vs Free-Air Temperature

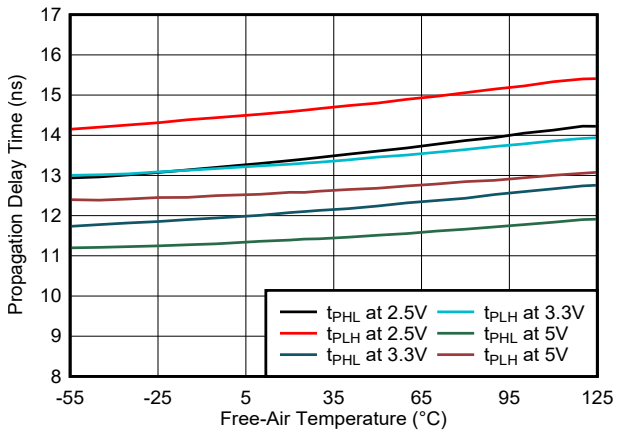
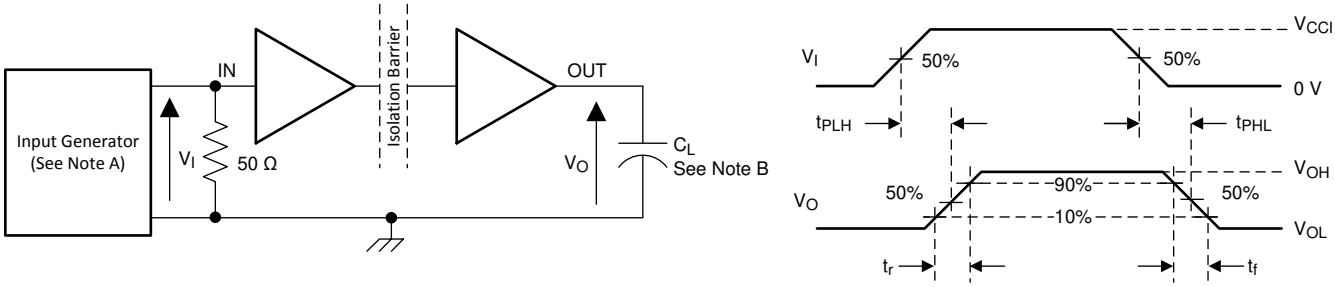


图 6-12. Propagation Delay Time vs Free-Air Temperature

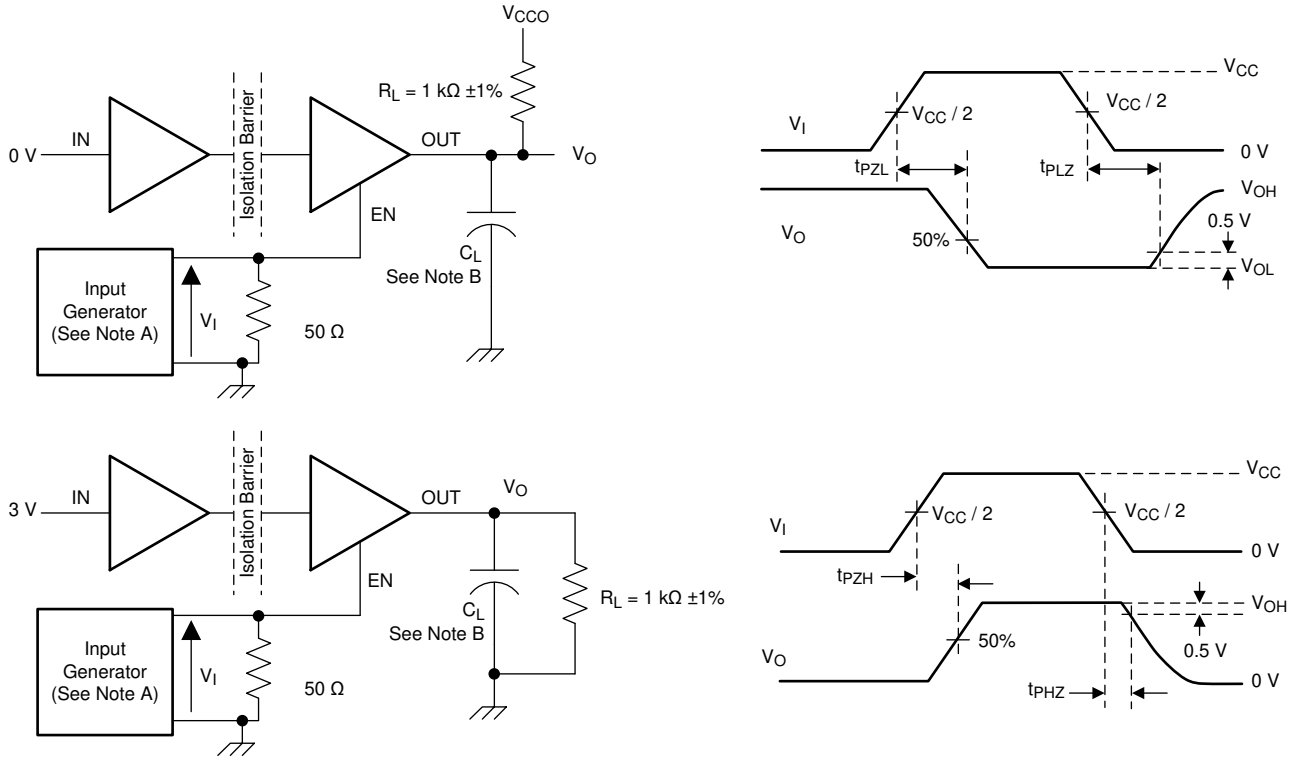
7 Parameter Measurement Information



A. The input pulse is supplied by a generator having the following characteristics: PRR ⩽ 50 kHz, 50% duty cycle, t_r ⩽ 3 ns, t_f ⩽ 3ns, Z_O = 50 Ω. At the input, 50 Ω resistor is required to terminate Input Generator signal. It is not needed in actual application.

B. C_L = 15 pF and includes instrumentation and fixture capacitance within ±20%.

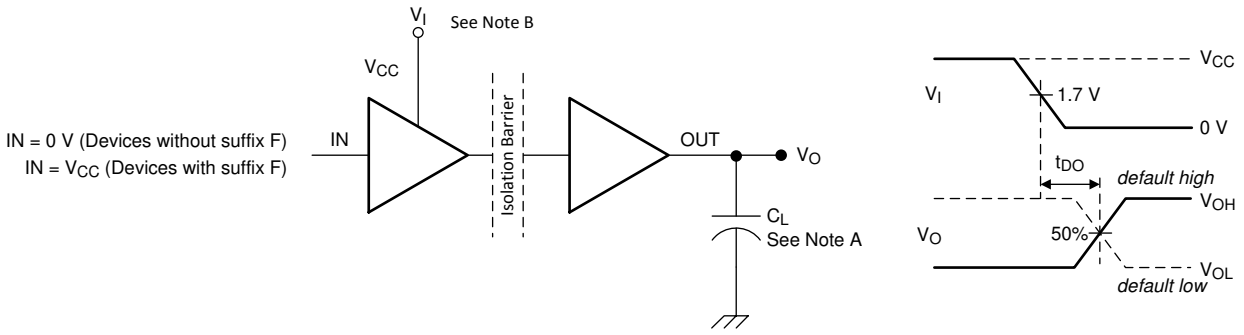
图 7-1. Switching Characteristics Test Circuit and Voltage Waveforms



A. The input pulse is supplied by a generator having the following characteristics: PRR ⩽ 10 kHz, 50% duty cycle, t_r ⩽ 3 ns, t_f ⩽ 3 ns, Z_O = 50 Ω.

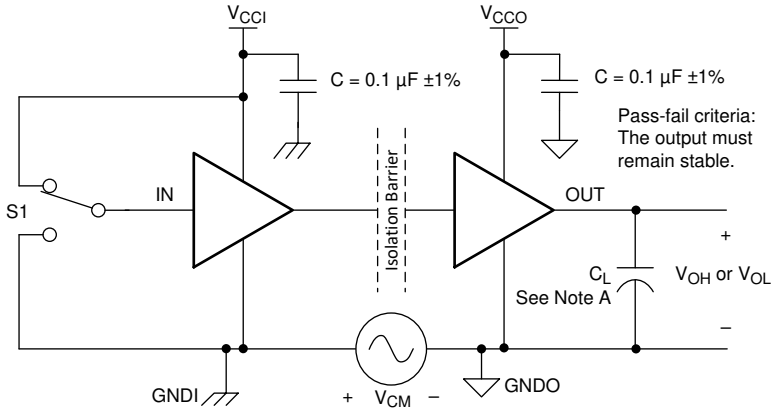
B. C_L = 15 pF and includes instrumentation and fixture capacitance within ±20%.

图 7-2. Enable/Disable Propagation Delay Time Test Circuit and Waveform



A. C_L = 15 pF and includes instrumentation and fixture capacitance within ±20%.
B. Power Supply Ramp Rate = 10 mV/ns

图 7-3. Default Output Delay Time Test Circuit and Voltage Waveforms



A. C_L = 15 pF and includes instrumentation and fixture capacitance within ±20%.

图 7-4. Common-Mode Transient Immunity Test Circuit

8 Detailed Description

8.1 Overview

The ISO773x-Q1 family of devices has an ON-OFF keying (OOK) modulation scheme to transmit the digital data across a silicon dioxide based isolation barrier. The transmitter sends a high frequency carrier across the barrier to represent one digital state and sends no signal to represent the other digital state. The receiver demodulates the signal after advanced signal conditioning and produces the output through a buffer stage. If the ENx pin is low then the output goes to high impedance. The ISO773x-Q1 family of devices also incorporates advanced circuit techniques to maximize the CMTI performance and minimize the radiated emissions due the high frequency carrier and IO buffer switching. The conceptual block diagram of a digital capacitive isolator, 图 8-1, shows a functional block diagram of a typical channel.

8.2 Functional Block Diagram

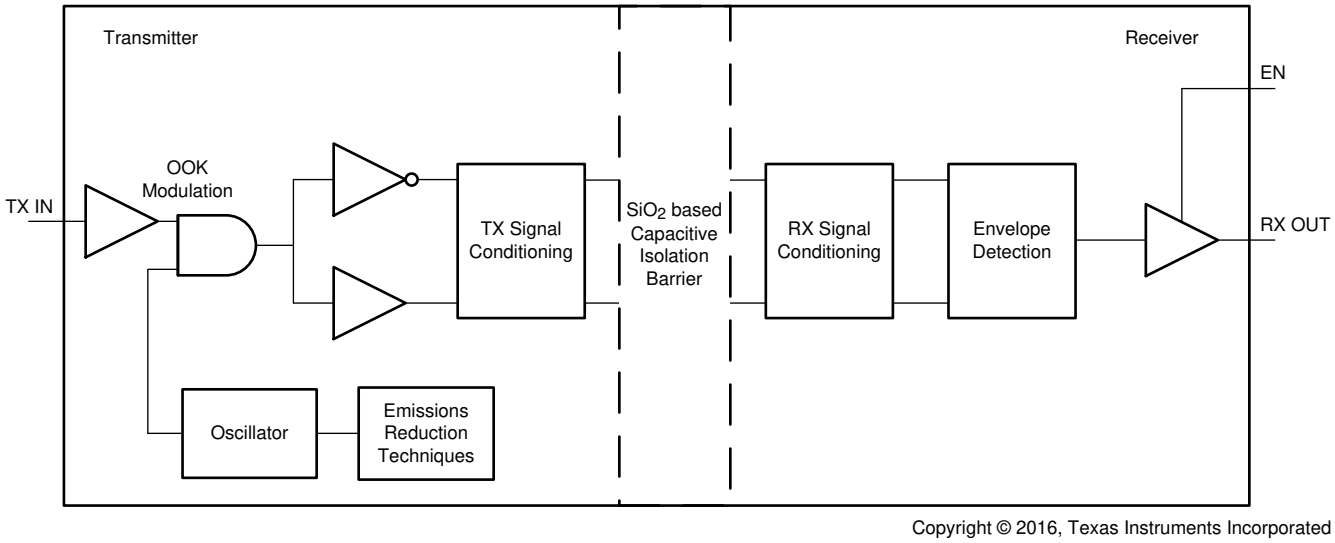


图 8-1. Conceptual Block Diagram of a Digital Capacitive Isolator

图 8-2 shows a conceptual detail of how the ON-OFF keying scheme works.

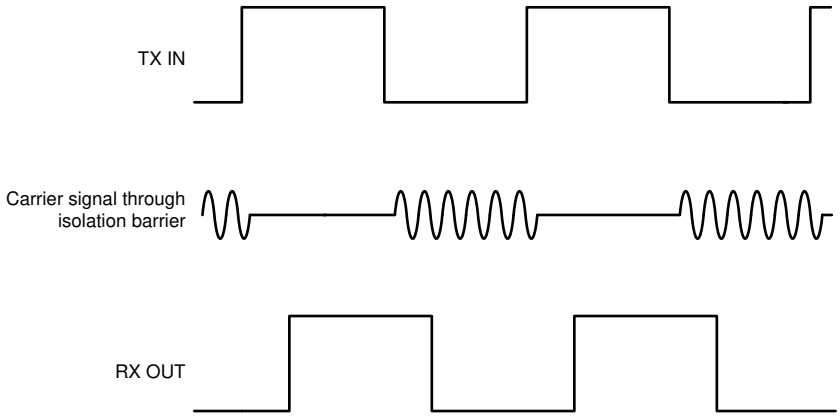


图 8-2. On-Off Keying (OOK) Based Modulation Scheme

8.3 Feature Description

表 8-1 provides an overview of the device features.

表 8-1. Device Features

PART NUMBER	CHANNEL DIRECTION	MAXIMUM DATA RATE	DEFAULT OUTPUT	PACKAGE	RATED ISOLATION(1)
ISO7730-Q1	3 Forward, 0 Reverse	100 Mbps	High	DW-16	5000 V_{RMS} / 8000 V_{PK}
				DBQ-16	3000 V_{RMS} / 4242 V_{PK}
ISO7730-Q1 with F suffix	3 Forward, 0 Reverse	100 Mbps	Low	DW-16	5000 V_{RMS} / 8000 V_{PK}
				DBQ-16	3000 V_{RMS} / 4242 V_{PK}
ISO7731-Q1	2 Forward, 1 Reverse	100 Mbps	High	DW-16	5000 V_{RMS} / 8000 V_{PK}
				DBQ-16	3000 V_{RMS} / 4242 V_{PK}
ISO7731-Q1 with F suffix	2 Forward, 1 Reverse	100 Mbps	Low	DW-16	5000 V_{RMS} / 8000 V_{PK}
				DBQ-16	3000 V_{RMS} / 4242 V_{PK}

(1) See 节 6.7 for detailed isolation ratings.

8.3.1 Electromagnetic Compatibility (EMC) Considerations

Many applications in harsh industrial environment are sensitive to disturbances such as electrostatic discharge (ESD), electrical fast transient (EFT), surge and electromagnetic emissions. These electromagnetic disturbances are regulated by international standards such as IEC 61000-4-x and CISPR 22. Although system-level performance and reliability depends, to a large extent, on the application board design and layout, the ISO773x-Q1 family of devices incorporates many chip-level design improvements for overall system robustness. Some of these improvements include:

- Robust ESD protection cells for input and output signal pins and inter-chip bond pads.
- Low-resistance connectivity of ESD cells to supply and ground pins.
- Enhanced performance of high voltage isolation capacitor for better tolerance of ESD, EFT and surge events.
- Bigger on-chip decoupling capacitors to bypass undesirable high energy signals through a low impedance path.
- PMOS and NMOS devices isolated from each other by using guard rings to avoid triggering of parasitic SCRs.
- Reduced common mode currents across the isolation barrier by ensuring purely differential internal operation.

8.4 Device Functional Modes

表 8-2 lists the functional modes for the ISO773x-Q1 devices.

表 8-2. Function Table

V_{CCI} (1)	V_{CCO}	INPUT (INx)(3)	OUTPUT ENABLE (ENx)	OUTPUT (OUTx)	COMMENTS
PU	PU	H	H or open	H	Normal Operation: A channel output assumes the logic state of its input.
		L	H or open	L	
		Open	H or open	Default	Default mode: When INx is open, the corresponding channel output goes to its default logic state. Default is *High* for ISO773x-Q1 and *Low* for ISO773x-Q1 with F suffix.
X	PU	X	L	Z	A low value of Output Enable causes the outputs to be high-impedance
PD	PU	X	H or open	Default	Default mode: When V_{CCI} is unpowered, a channel output assumes the logic state based on the selected default option. Default is *High* for ISO773x-Q1 and *Low* for ISO773x-Q1 with F suffix. When V_{CCI} transitions from unpowered to powered-up, a channel output assumes the logic state of its input. When V_{CCI} transitions from powered-up to unpowered, channel output assumes the selected default state.
X	PD	X	X	Undetermined	When V_{CCO} is unpowered, a channel output is undetermined(2). When V_{CCO} transitions from unpowered to powered-up, a channel output assumes the logic state of its input

(1) V_{CCI} = Input-side V_{CC}; V_{CCO} = Output-side V_{CC}; PU = Powered up ($V_{CC} \geq 2.25$ V); PD = Powered down ($V_{CC} \leq 1.7$ V); X = Irrelevant; H = High level; L = Low level ; Z = High Impedance
(2) The outputs are in undetermined state when 1.7 V < V_{CCI}, V_{CCO} < 2.25 V.
(3) A strongly driven input signal can weakly power the floating V_{CC} via an internal protection diode and cause undetermined output.

8.4.1 Device I/O Schematics

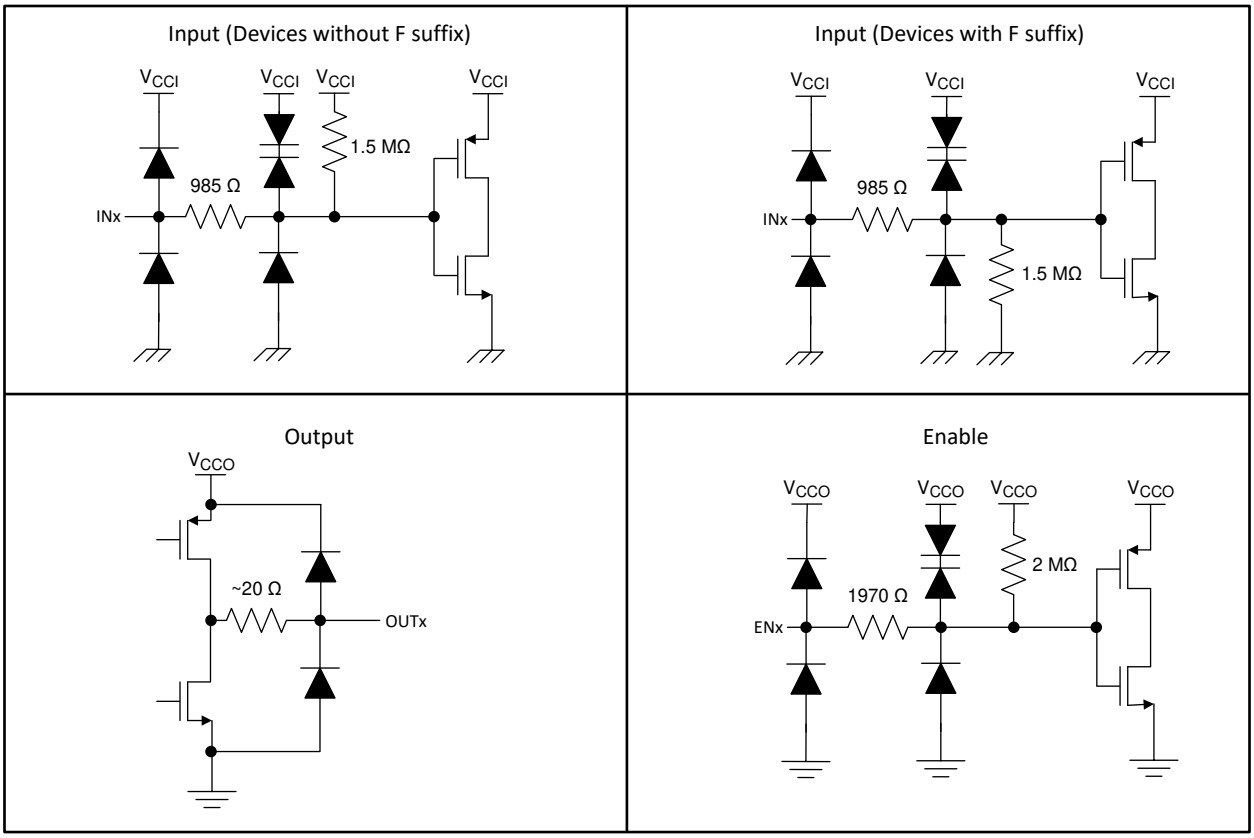


图 8-3. Device I/O Schematics

9 Application and Implementation

备注

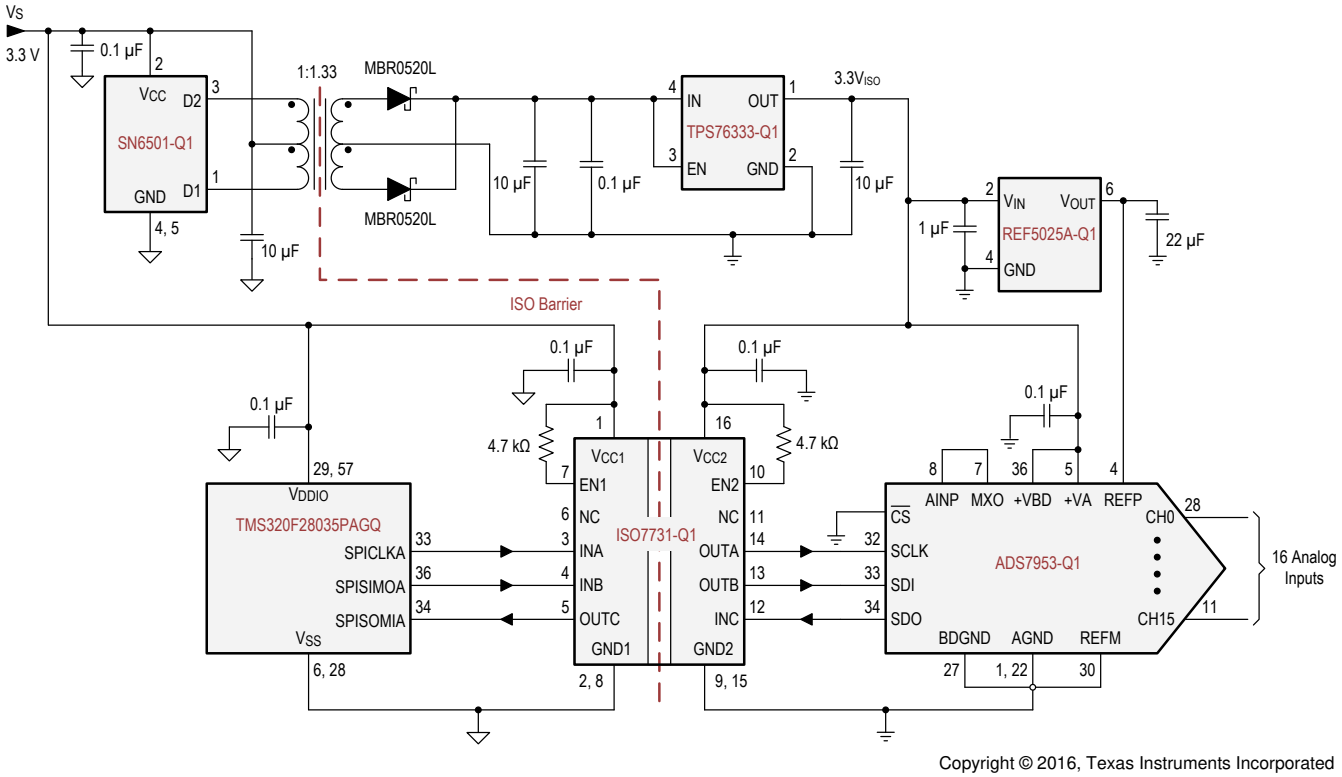
以下应用部分中的信息不属于 TI 器件规格的范围，TI 不担保其准确性和完整性。TI 的客 户应负责确定器件是否适用于其应用。客户应验证并测试其设计，以确保系统功能。

9.1 Application Information

The ISO773x-Q1 devices are high-performance, triple-channel digital isolators. These devices come with enable pins on each side which can be used to put the respective outputs in high impedance for multi-master driving applications and reduce power consumption. The ISO773x-Q1 family of devices use single-ended CMOS-logic switching technology. The voltage range is from 2.25 V to 5.5 V for both supplies, V_{CC1} and V_{CC2}. When designing with digital isolators, keep in mind that because of the single-ended design structure, digital isolators do not conform to any specific interface standard and are only intended for isolating single-ended CMOS or TTL digital signal lines. The isolator is typically placed between the data controller (that is, µC or UART), and a data converter or a line transceiver, regardless of the interface type or standard.

9.2 Typical Application

The ISO7731-Q1 device combined with Texas Instruments' Piccolo™ microcontroller, analog-to-digital receiver, transformer driver, and voltage regulator can create an isolated serial peripheral interface (SPI) as shown in 图 9-1.



Multiple pins and discrete components are omitted for clarity.

图 9-1. Isolated SPI for an Analog Input Module With 16 Inputs and a Single Slave

9.2.1 Design Requirements

To design with these devices, use the parameters listed in 表 9-1.

表 9-1. Design Parameters

PARAMETER	VALUE
Supply voltage, V_{CC1} and V_{CC2}	2.25 to 5.5 V
Decoupling capacitor between V_{CC1} and GND1	0.1 µF
Decoupling capacitor from V_{CC2} and GND2	0.1 µF

9.2.2 Detailed Design Procedure

Unlike optocouplers, which require external components to improve performance, provide bias, or limit current, the ISO773x-Q1 family of devices only requires two external bypass capacitors to operate. 图 9-2 and 图 9-3 show the typical circuit hook-up for the devices.

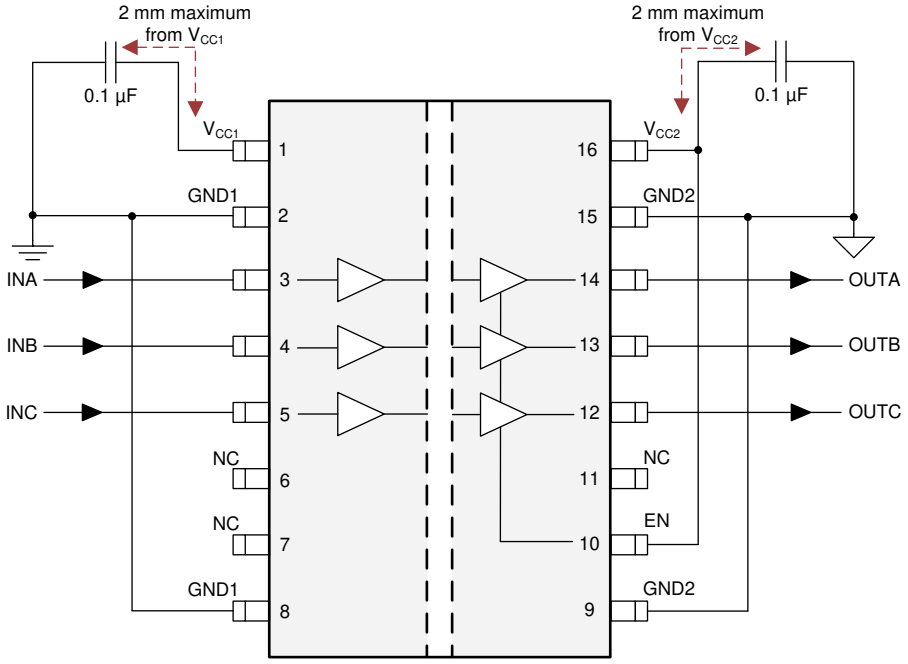


图 9-2. Typical ISO7730-Q1 Circuit Hook-Up

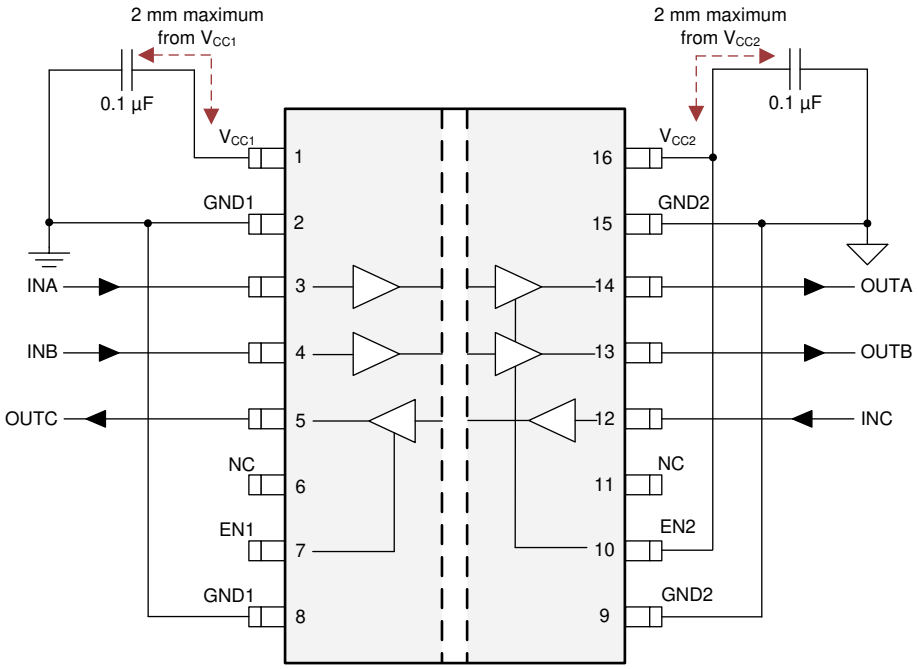


图 9-3. Typical ISO7731-Q1 Circuit Hook-Up

9.2.3 Application Curves

The following typical eye diagrams of the ISO773x-Q1 family of devices indicate low jitter and wide open eye at the maximum data rate of 100 Mbps.

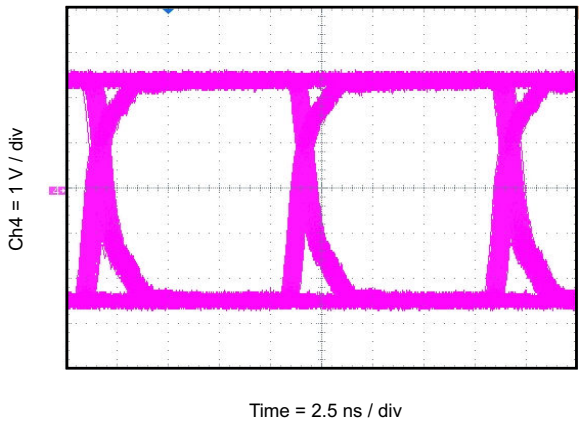


图 9-4. Eye Diagram at 100 Mbps PRBS 2^{16} – 1, 5 V and 25°C

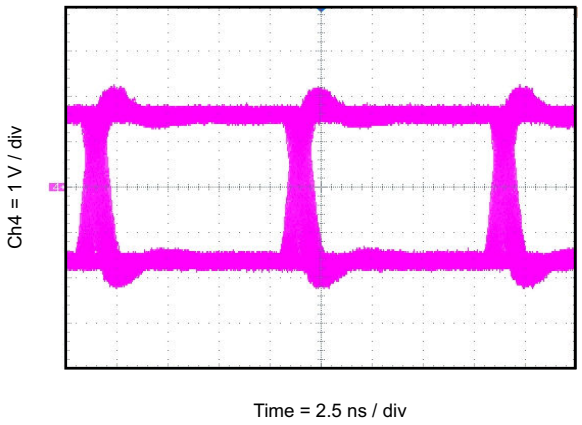


图 9-5. Eye Diagram at 100 Mbps PRBS 2^{16} – 1, 3.3 V and 25°C

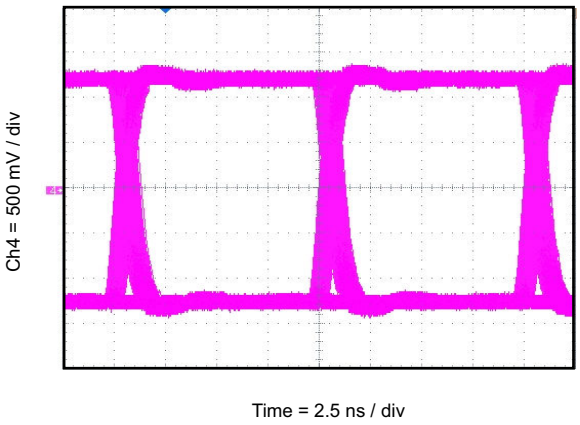


图 9-6. Eye Diagram at 100 Mbps PRBS 2^{16} – 1, 2.5 V and 25°C

9.2.3.1 Insulation Lifetime

Insulation lifetime projection data is collected by using industry-standard Time Dependent Dielectric Breakdown (TDDB) test method. In this test, all pins on each side of the barrier are tied together creating a two-terminal device and high voltage applied between the two sides; See 图 9-7 for TDDB test setup. The insulation breakdown data is collected at various high voltages switching at 60 Hz over temperature. For reinforced insulation, VDE standard requires the use of TDDB projection line with failure rate of less than 1 part per million (ppm). Even though the expected minimum insulation lifetime is 20 years at the specified working isolation voltage, VDE reinforced certification requires additional safety margin of 20% for working voltage and 50% for lifetime which translates into minimum required insulation lifetime of 30 years at a working voltage that's 20% higher than the specified value.

图 9-8 shows the intrinsic capability of the isolation barrier to withstand high voltage stress over its lifetime. Based on the TDDB data, the intrinsic capability of the insulation is 1500 V_{RMS} with a lifetime of 169 years. Other factors, such as package size, pollution degree, material group, etc. can further limit the working voltage of the component. The working voltage of DW-16 package is specified upto 1500 V_{RMS} and DBQ-16 package up to 400 V_{RMS}. At the lower working voltages, the corresponding insulation lifetime is much longer than 169 years.

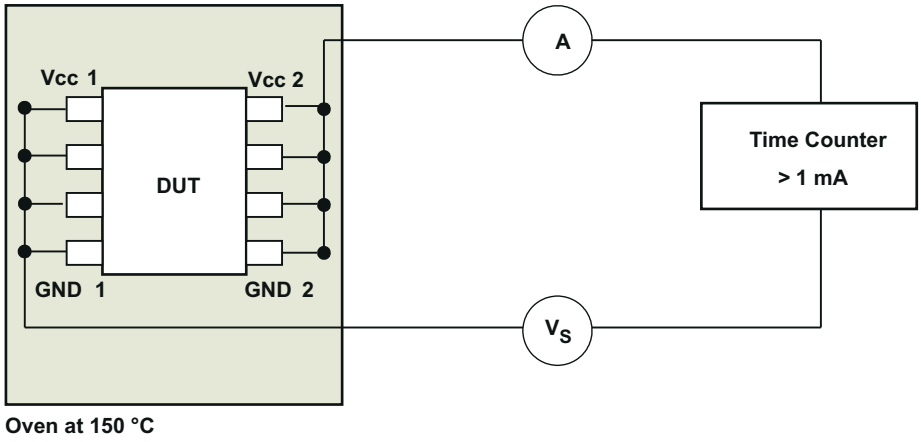


图 9-7. Test Setup for Insulation Lifetime Measurement

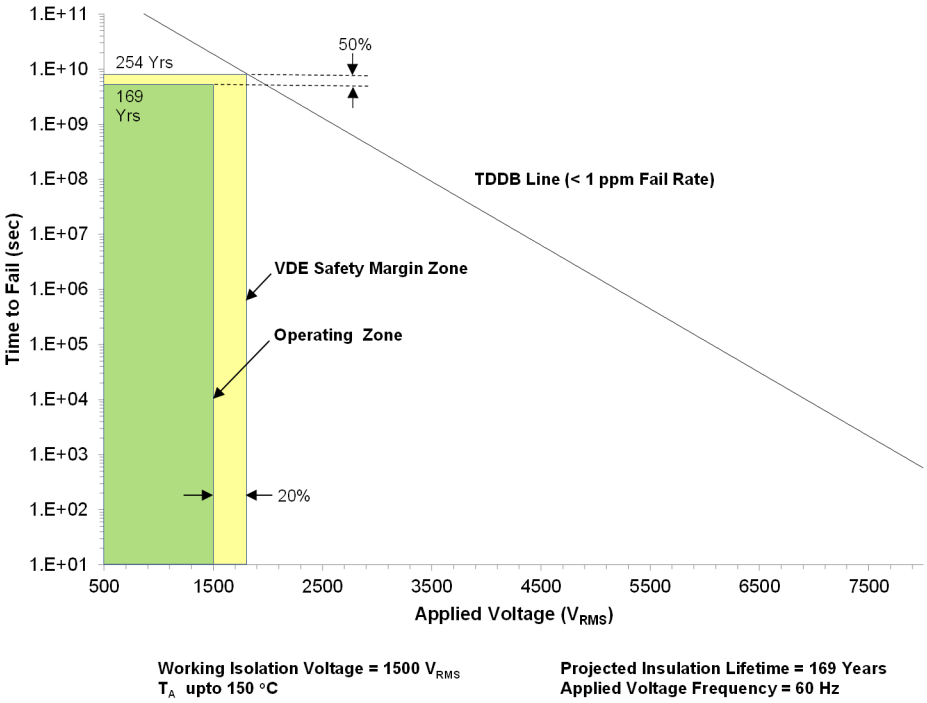


图 9-8. Insulation Lifetime Projection Data

10 Power Supply Recommendations

To help ensure reliable operation at data rates and supply voltages, a 0.1- μ F bypass capacitor is recommended at the input and output supply pins (V_{CC1} and V_{CC2}). The capacitors should be placed as close to the supply pins as possible. If only a single primary-side power supply is available in an application, isolated power can be generated for the secondary-side with the help of a transformer driver such as Texas Instruments' SN6501-Q1. For such applications, detailed power supply design and transformer selection recommendations are available in the *SN6501-Q1 Transformer Driver for Isolated Power Supplies* data sheet.

11 Layout

11.1 Layout Guidelines

A minimum of four layers is required to accomplish a low EMI PCB design (see 图 11-1). Layer stacking should be in the following order (top-to-bottom): high-speed signal layer, ground plane, power plane and low-frequency signal layer.

- Routing the high-speed traces on the top layer avoids the use of vias (and the introduction of their inductances) and allows for clean interconnects between the isolator and the transmitter and receiver circuits of the data link.
- Placing a solid ground plane next to the high-speed signal layer establishes controlled impedance for transmission line interconnects and provides an excellent low-inductance path for the return current flow.
- Placing the power plane next to the ground plane creates additional high-frequency bypass capacitance of approximately 100 pF/inch^2.
- Routing the slower speed control signals on the bottom layer allows for greater flexibility as these signal links usually have margin to tolerate discontinuities such as vias.

If an additional supply voltage plane or signal layer is needed, add a second power or ground plane system to the stack to keep it symmetrical. This makes the stack mechanically stable and prevents it from warping. Also the power and ground plane of each power system can be placed closer together, thus increasing the high-frequency bypass capacitance significantly.

For detailed layout recommendations, refer to the *Digital Isolator Design Guide*.

11.1.1 PCB Material

For digital circuit boards operating below 150 Mbps, (or rise and fall times higher than 1 ns), and trace lengths of up to 10 inches, use standard FR-4 UL94V-0 printed circuit boards. This PCB is preferred over cheaper alternatives due to its lower dielectric losses at high frequencies, less moisture absorption, greater strength and stiffness, and self-extinguishing flammability-characteristics.

11.2 Layout Example

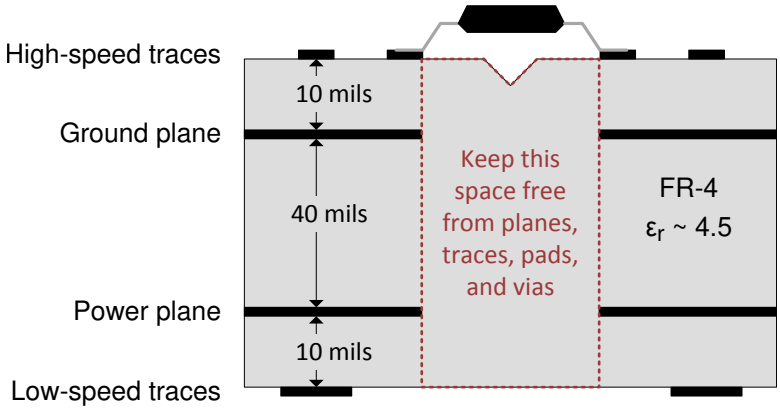


图 11-1. Layout Example Schematic

12 Device and Documentation Support

12.1 Documentation Support

12.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, *Digital Isolator Design Guide*
- Texas Instruments, *Isolation Glossary*
- Texas Instruments, *How to use isolation to improve ESD, EFT, and Surge immunity in industrial systems* application report
- Texas Instruments, *REF50xxA-Q1 Low-Noise, Very Low Drift, Precision Voltage Reference* data sheet
- Texas Instruments, *SN6501-Q1 Transformer Driver for Isolated Power Supplies* data sheet
- Texas Instruments, TPS76333-Q1 *Low-Power 150-mA Low-Dropout Linear Regulators* data sheet
- Texas Instruments, TMS320F28035 *Piccolo™ Microcontrollers* data sheet

12.2 Related Links

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

表 12-1. Related Links

PARTS	PRODUCT FOLDER	ORDER NOW	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
ISO7730-Q1	Click here	Click here	Click here	Click here	Click here
ISO7731-Q1	Click here	Click here	Click here	Click here	Click here

12.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.4 支持资源

TI E2E™ 支持论坛是工程师的重要参考资料，可直接从专家获得快速、经过验证的解答和设计帮助。搜索现有解答或提出自己的问题可获得所需的快速设计帮助。

链接的内容由各个贡献者“按原样”提供。这些内容并不构成 TI 技术规范，并且不一定反映 TI 的观点；请参阅 TI 的《使用条款》。

12.5 Trademarks

Piccolo™ is a trademark of Texas Instruments.
TI E2E™ is a trademark of Texas Instruments.
所有商标均为其各自所有者的财产。

12.6 静电放电警告

静电放电 (ESD) 会损坏这个集成电路。德州仪器 (TI) 建议通过适当的预防措施处理所有集成电路。如果不遵守正确的处理和安装程序，可能会损坏集成电路。

ESD 的损坏小至导致微小的性能降级，大至整个器件故障。精密的集成电路可能更容易受到损坏，这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

12.7 术语表

TI 术语表　　本术语表列出并解释了术语、首字母缩略词和定义。

13 Mechanical, Packaging, and Orderable Information

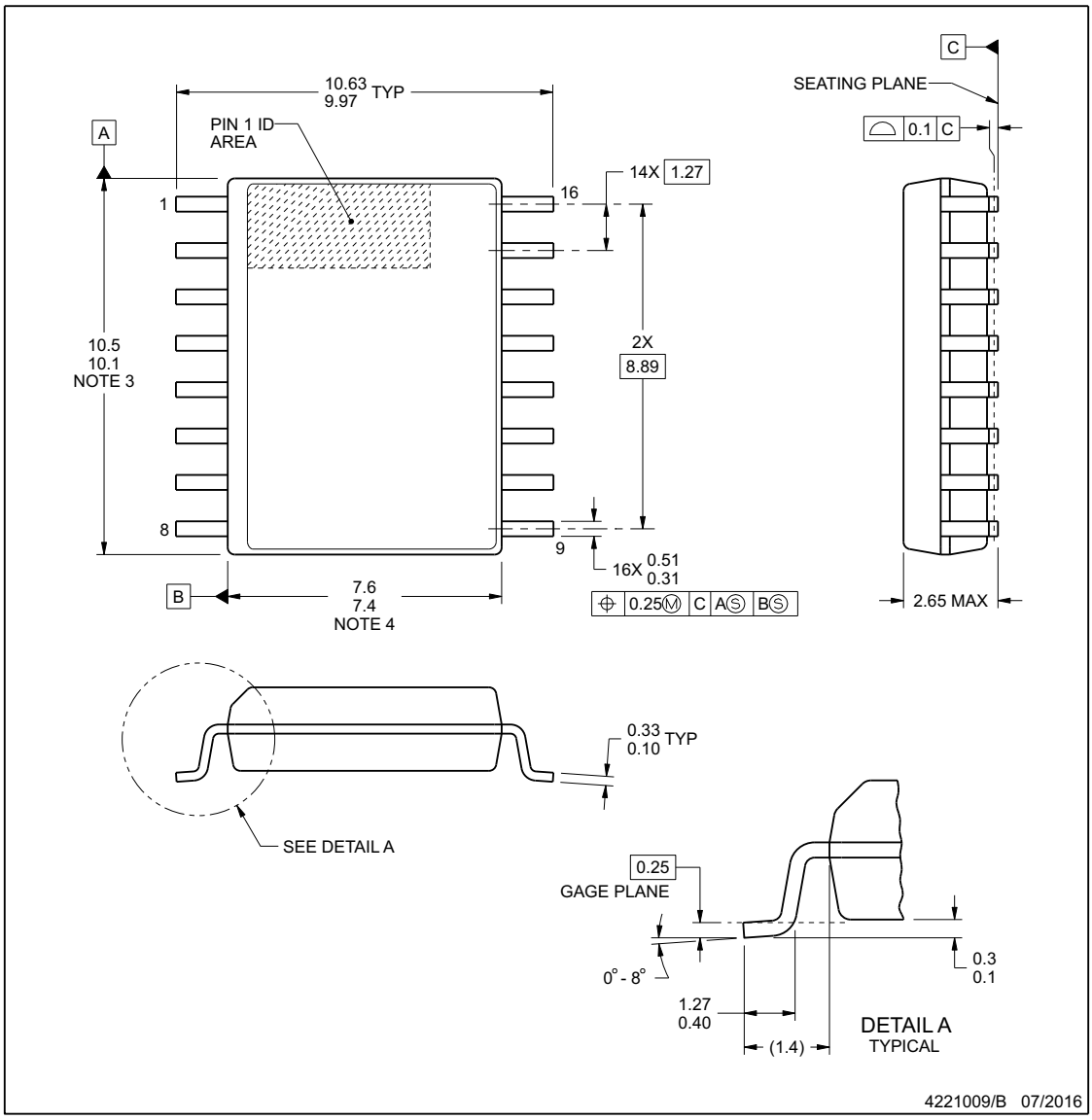
The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGE OUTLINE

DW0016B

SOIC - 2.65 mm max height

SOIC



NOTES:

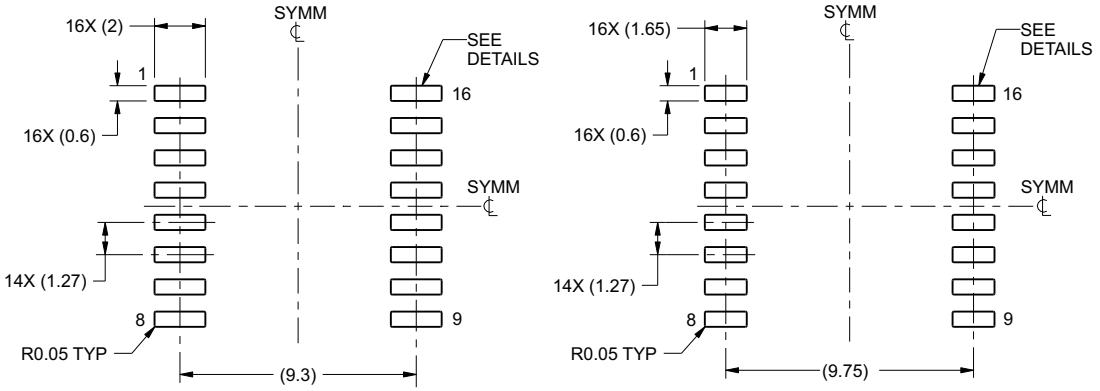
1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm, per side.
5. Reference JEDEC registration MS-013.

EXAMPLE BOARD LAYOUT

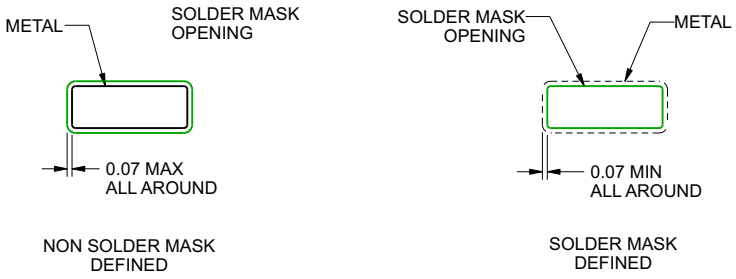
DW0016B

SOIC - 2.65 mm max height

SOIC



LAND PATTERN EXAMPLE
SCALE:4X



SOLDER MASK DETAILS

4221009/B 07/2016

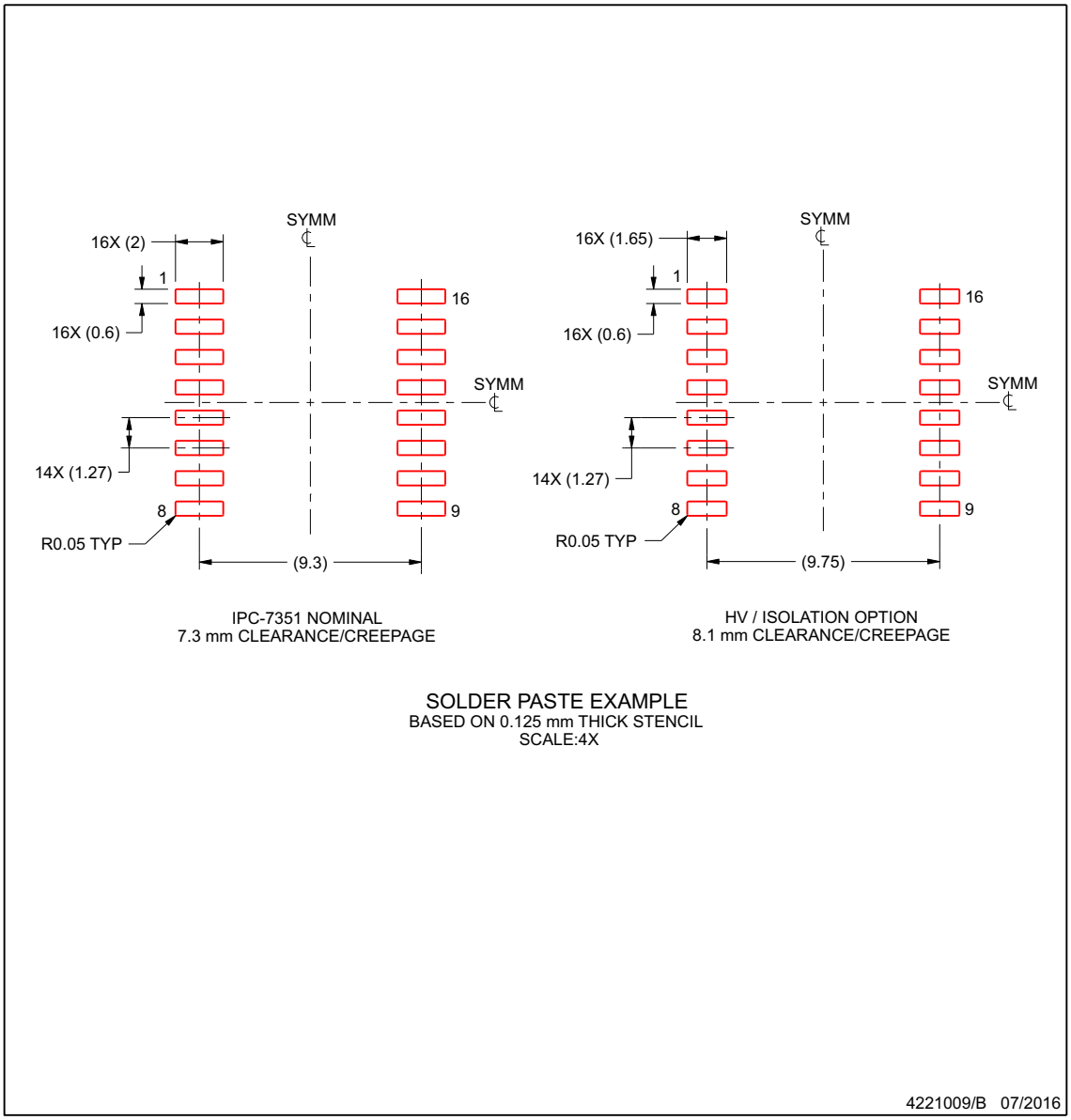
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

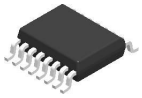
DW0016B — **SOIC - 2.65 mm max height**

SOIC



NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

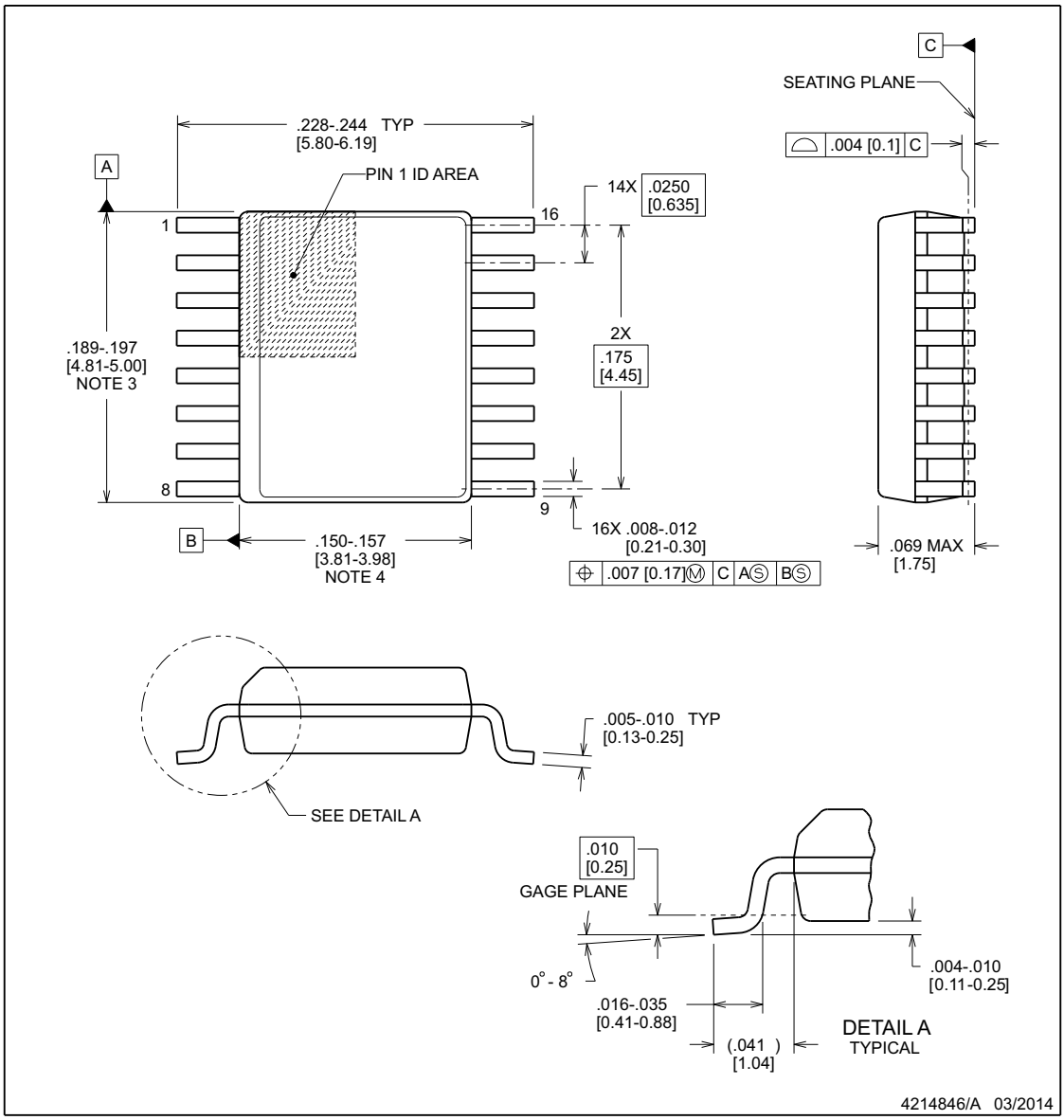


PACKAGE OUTLINE

DBQ0016A

SSOP - 1.75 mm max height

SHRINK SMALL-OUTLINE PACKAGE



NOTES:

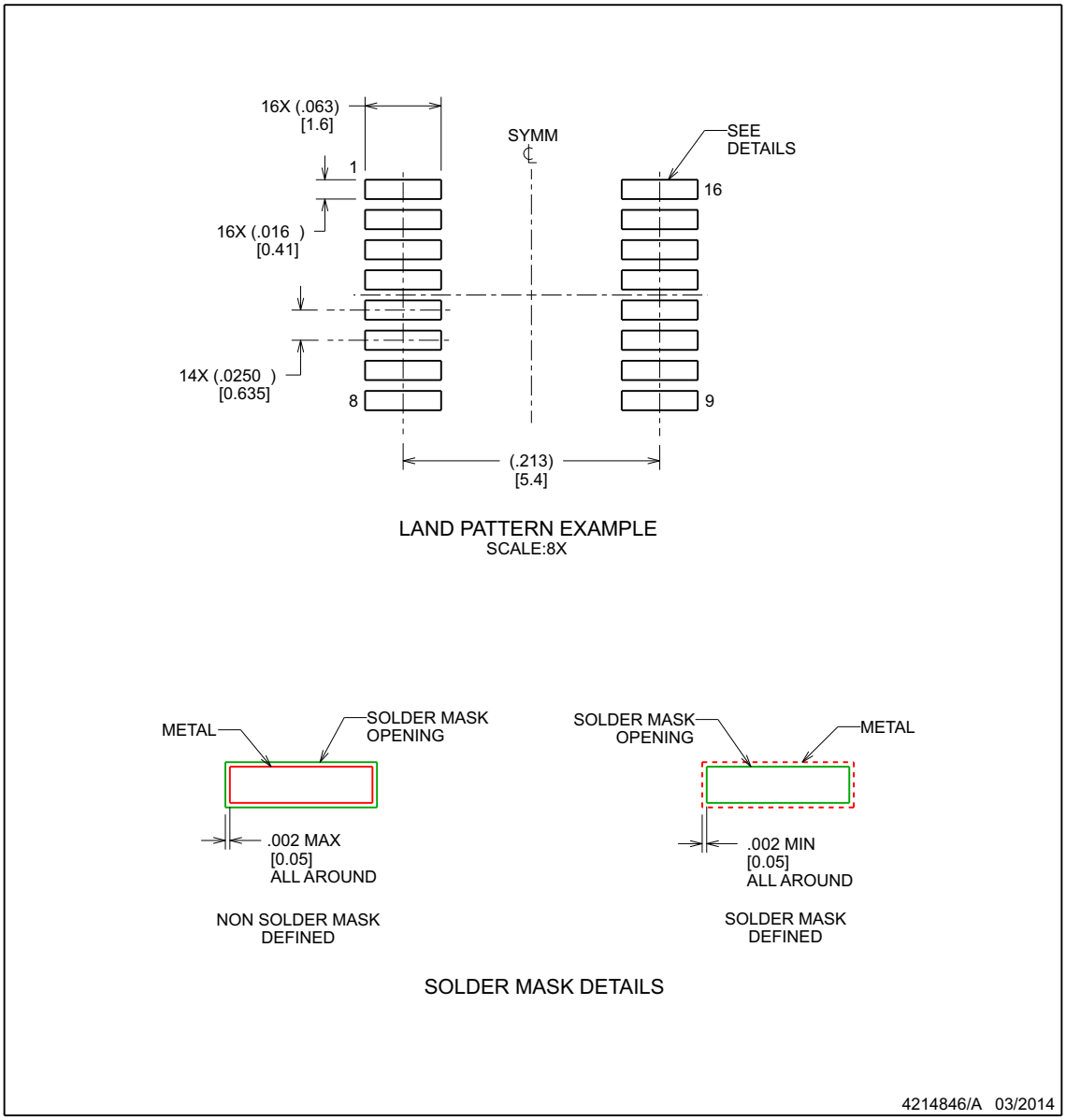
1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 inch, per side.
4. This dimension does not include interlead flash.
5. Reference JEDEC registration MO-137, variation AB.

EXAMPLE BOARD LAYOUT

DBQ0016A

SSOP - 1.75 mm max height

SHRINK SMALL-OUTLINE PACKAGE



NOTES: (continued)

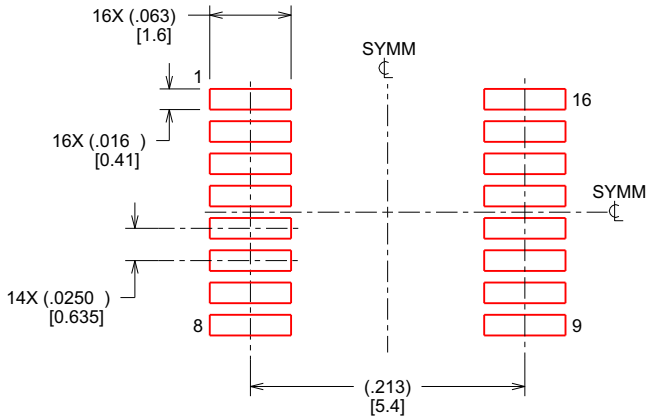
6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

DBQ0016A

SSOP - 1.75 mm max height

SHRINK SMALL-OUTLINE PACKAGE



SOLDER PASTE EXAMPLE
BASED ON .005 INCH [0.127 MM] THICK STENCIL
SCALE:8X

4214846/A 03/2014

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
ISO7730FQDBQQ1	LIFEBUY	SSOP	DBQ	16	75	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	7730FQ	
ISO7730FQDBQRQ1	ACTIVE	SSOP	DBQ	16	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	7730FQ	Samples
ISO7730FQDWQ1	LIFEBUY	SOIC	DW	16	40	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	ISO7730FQ	
ISO7730FQDWRQ1	ACTIVE	SOIC	DW	16	2000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	(ISO7730F, ISO7730 FQ)	Samples
ISO7730QDBQQ1	LIFEBUY	SSOP	DBQ	16	75	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	7730Q	
ISO7730QDBQRQ1	ACTIVE	SSOP	DBQ	16	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	7730Q	Samples
ISO7730QDWQ1	LIFEBUY	SOIC	DW	16	40	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	ISO7730Q	
ISO7730QDWRQ1	ACTIVE	SOIC	DW	16	2000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	(ISO7730, ISO7730Q)	Samples
ISO7731FQDBQQ1	LIFEBUY	SSOP	DBQ	16	75	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	7731FQ	
ISO7731FQDBQRQ1	ACTIVE	SSOP	DBQ	16	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	7731FQ	Samples
ISO7731FQDWQ1	LIFEBUY	SOIC	DW	16	40	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	ISO7731FQ	
ISO7731FQDWRQ1	ACTIVE	SOIC	DW	16	2000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	(ISO7731F, ISO7731 FQ)	Samples
ISO7731QDBQQ1	LIFEBUY	SSOP	DBQ	16	75	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	7731Q	
ISO7731QDBQRQ1	ACTIVE	SSOP	DBQ	16	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	7731Q	Samples
ISO7731QDWQ1	LIFEBUY	SOIC	DW	16	40	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	ISO7731Q	
ISO7731QDWRQ1	ACTIVE	SOIC	DW	16	2000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	(ISO7731, ISO7731Q)	Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.
Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

OTHER QUALIFIED VERSIONS OF ISO7730-Q1, ISO7731-Q1 :

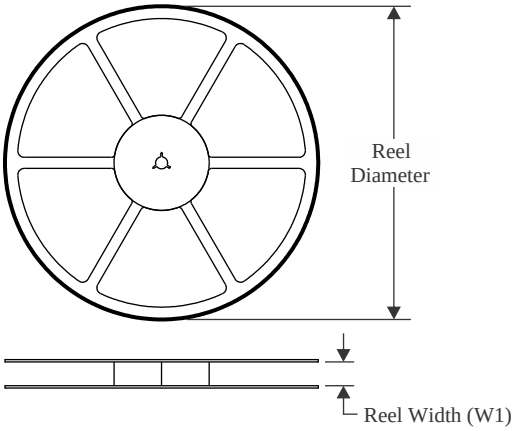
- Catalog : ISO7730, ISO7731

NOTE: Qualified Version Definitions:

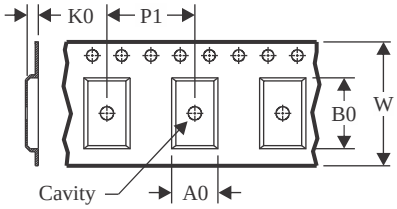
- Catalog - TI's standard catalog product

TAPE AND REEL INFORMATION

REEL DIMENSIONS

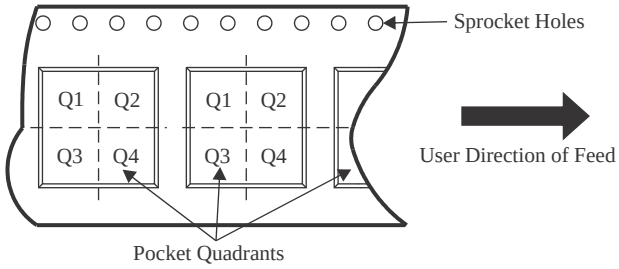


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

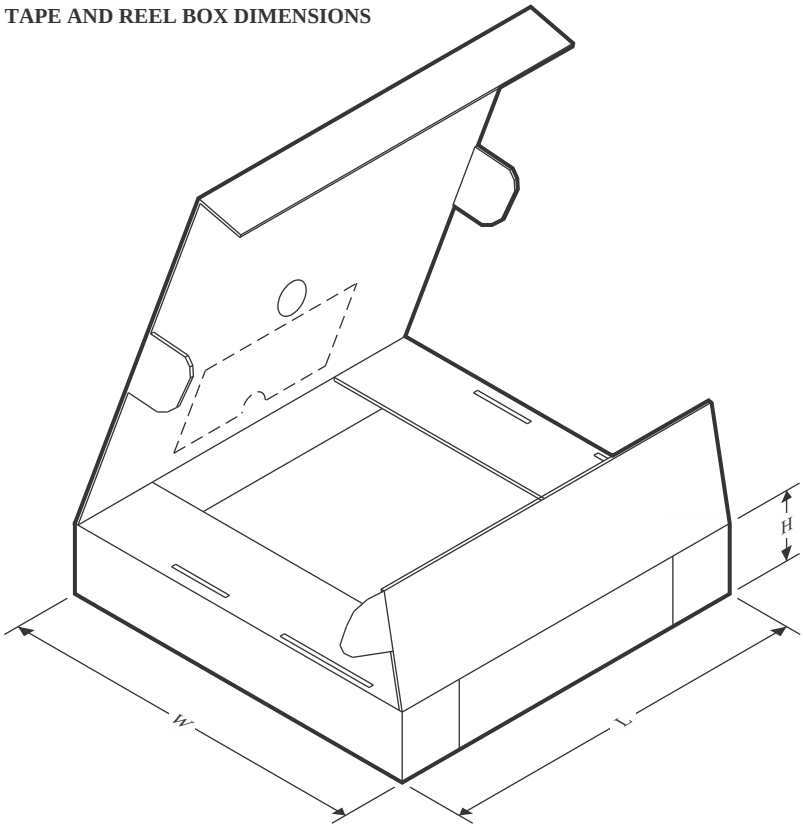


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO7730FQDBQRQ1	SSOP	DBQ	16	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO7730FQDBQRQ1	SSOP	DBQ	16	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO7730FQDWRQ1	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7730FQDWRQ1	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7730FQDWRQ1	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7730QDBQRQ1	SSOP	DBQ	16	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO7730QDBQRQ1	SSOP	DBQ	16	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO7730QDWRQ1	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7730QDWRQ1	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7730QDWRQ1	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7731FQDBQRQ1	SSOP	DBQ	16	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO7731FQDBQRQ1	SSOP	DBQ	16	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO7731FQDWRQ1	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7731FQDWRQ1	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7731FQDWRQ1	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7731QDBQRQ1	SSOP	DBQ	16	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO7731QDBQRQ1	SSOP	DBQ	16	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO7731QDWRQ1	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7731QDWRQ1	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7731QDWRQ1	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1

TAPE AND REEL BOX DIMENSIONS

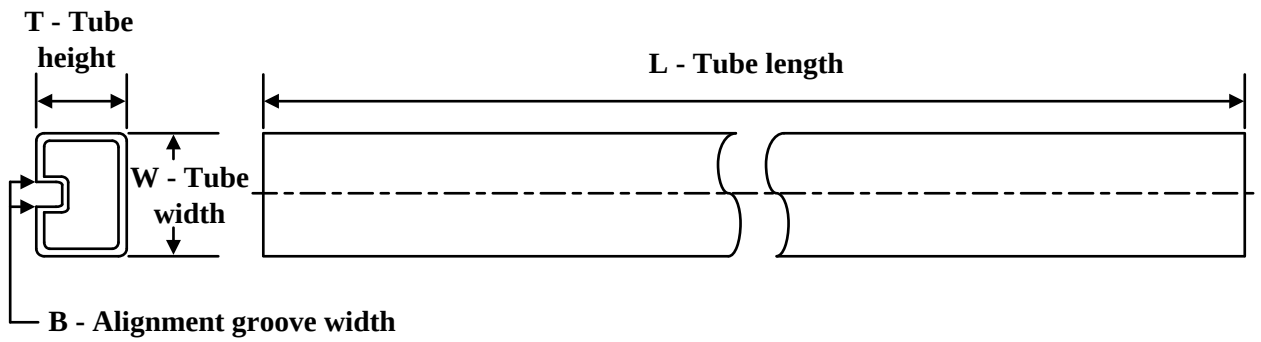


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ISO7730FQDBQRQ1	SSOP	DBQ	16	2500	350.0	350.0	43.0
ISO7730FQDBQRQ1	SSOP	DBQ	16	2500	350.0	350.0	43.0
ISO7730FQDWRQ1	SOIC	DW	16	2000	356.0	356.0	35.0
ISO7730FQDWRQ1	SOIC	DW	16	2000	356.0	356.0	35.0
ISO7730FQDWRQ1	SOIC	DW	16	2000	367.0	367.0	45.0
ISO7730QDBQRQ1	SSOP	DBQ	16	2500	350.0	350.0	43.0
ISO7730QDBQRQ1	SSOP	DBQ	16	2500	350.0	350.0	43.0
ISO7730QDWRQ1	SOIC	DW	16	2000	367.0	367.0	45.0
ISO7730QDWRQ1	SOIC	DW	16	2000	356.0	356.0	35.0
ISO7730QDWRQ1	SOIC	DW	16	2000	356.0	356.0	35.0
ISO7731FQDBQRQ1	SSOP	DBQ	16	2500	350.0	350.0	43.0
ISO7731FQDBQRQ1	SSOP	DBQ	16	2500	350.0	350.0	43.0
ISO7731FQDWRQ1	SOIC	DW	16	2000	356.0	356.0	35.0
ISO7731FQDWRQ1	SOIC	DW	16	2000	367.0	367.0	45.0
ISO7731FQDWRQ1	SOIC	DW	16	2000	356.0	356.0	35.0
ISO7731QDBQRQ1	SSOP	DBQ	16	2500	350.0	350.0	43.0
ISO7731QDBQRQ1	SSOP	DBQ	16	2500	350.0	350.0	43.0
ISO7731QDWRQ1	SOIC	DW	16	2000	356.0	356.0	35.0

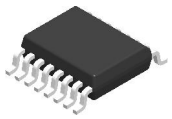
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ISO7731QDWRQ1	SOIC	DW	16	2000	356.0	356.0	35.0
ISO7731QDWRQ1	SOIC	DW	16	2000	367.0	367.0	45.0

TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
ISO7730FQDBQQ1	DBQ	SSOP	16	75	505.46	6.76	3810	4
ISO7730FQDWQ1	DW	SOIC	16	40	506.98	12.7	4826	6.6
ISO7730FQDWQ1	DW	SOIC	16	40	507	12.83	5080	6.6
ISO7730QDBQQ1	DBQ	SSOP	16	75	505.46	6.76	3810	4
ISO7730QDWQ1	DW	SOIC	16	40	507	12.83	5080	6.6
ISO7730QDWQ1	DW	SOIC	16	40	506.98	12.7	4826	6.6
ISO7731FQDBQQ1	DBQ	SSOP	16	75	505.46	6.76	3810	4
ISO7731FQDWQ1	DW	SOIC	16	40	506.98	12.7	4826	6.6
ISO7731FQDWQ1	DW	SOIC	16	40	507	12.83	5080	6.6
ISO7731QDBQQ1	DBQ	SSOP	16	75	505.46	6.76	3810	4
ISO7731QDWQ1	DW	SOIC	16	40	506.98	12.7	4826	6.6
ISO7731QDWQ1	DW	SOIC	16	40	507	12.83	5080	6.6

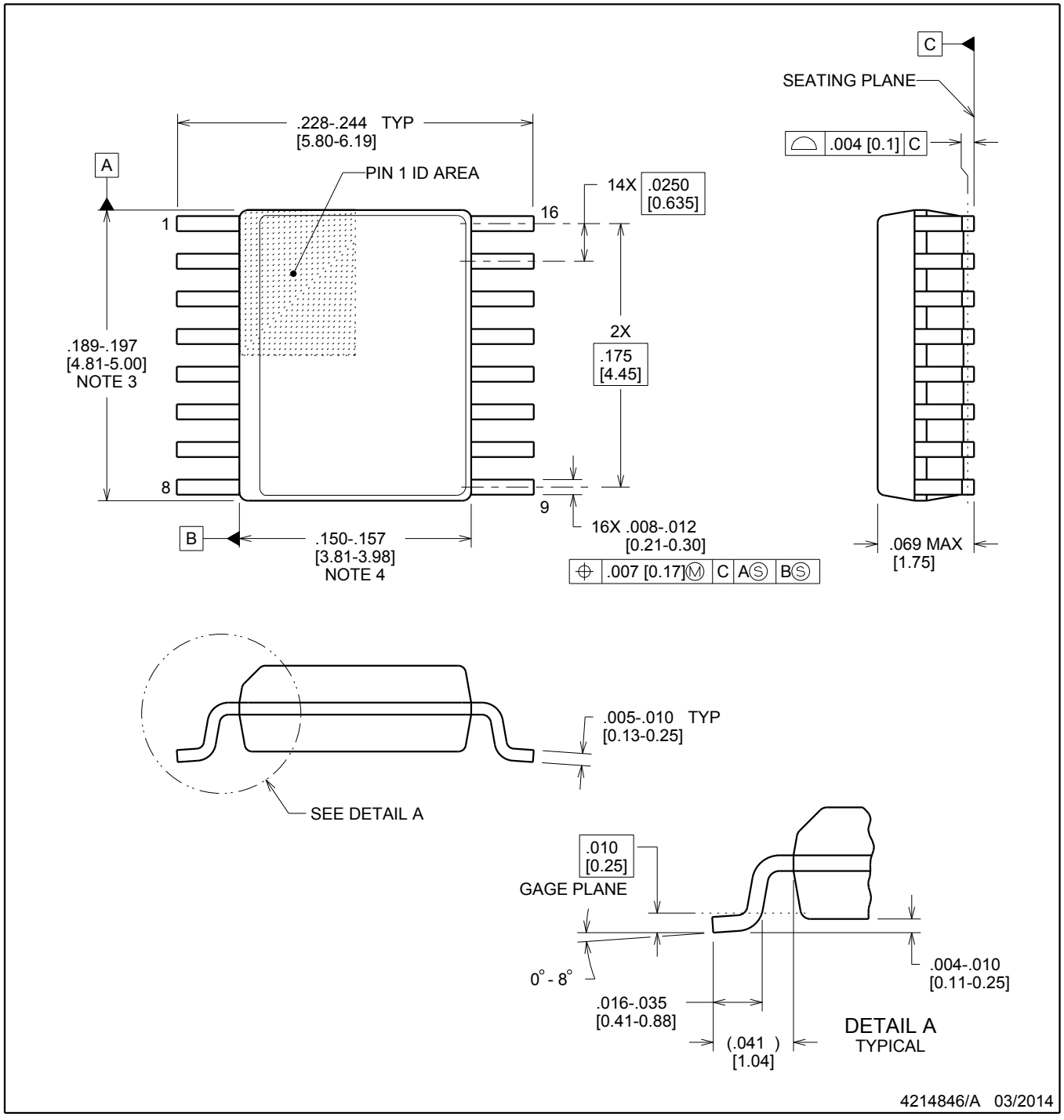


PACKAGE OUTLINE

DBQ0016A

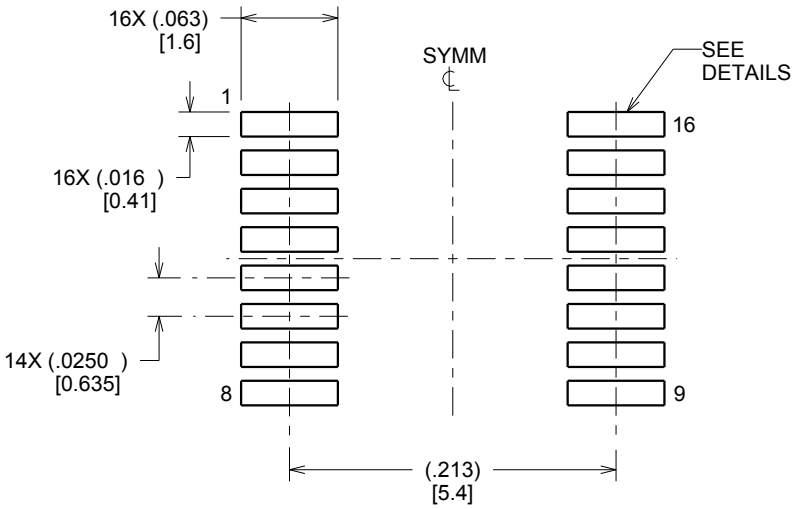
SSOP - 1.75 mm max height

SHRINK SMALL-OUTLINE PACKAGE

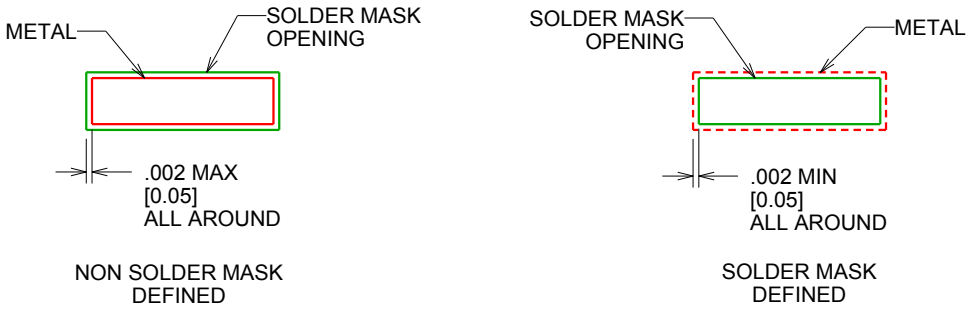


NOTES:

1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 inch, per side.
4. This dimension does not include interlead flash.
5. Reference JEDEC registration MO-137, variation AB.



LAND PATTERN EXAMPLE
SCALE:8X



SOLDER MASK DETAILS

4214846/A 03/2014

NOTES: (continued)

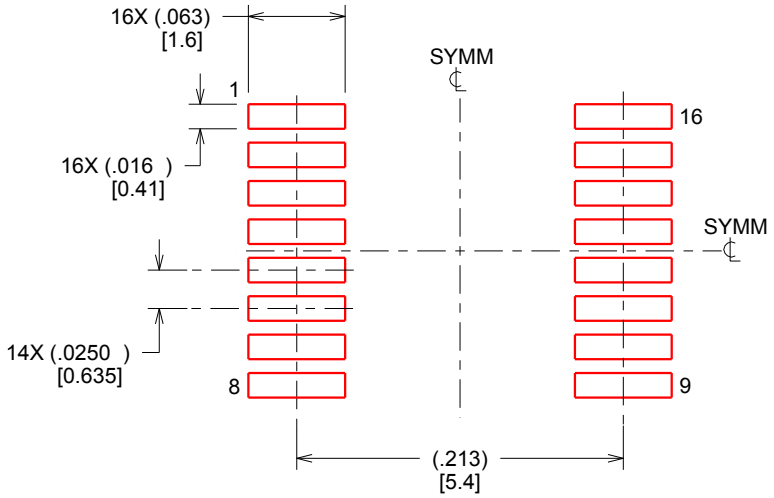
6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

DBQ0016A

SSOP - 1.75 mm max height

SHRINK SMALL-OUTLINE PACKAGE



SOLDER PASTE EXAMPLE
BASED ON .005 INCH [0.127 MM] THICK STENCIL
SCALE:8X

4214846/A 03/2014

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

GENERIC PACKAGE VIEW

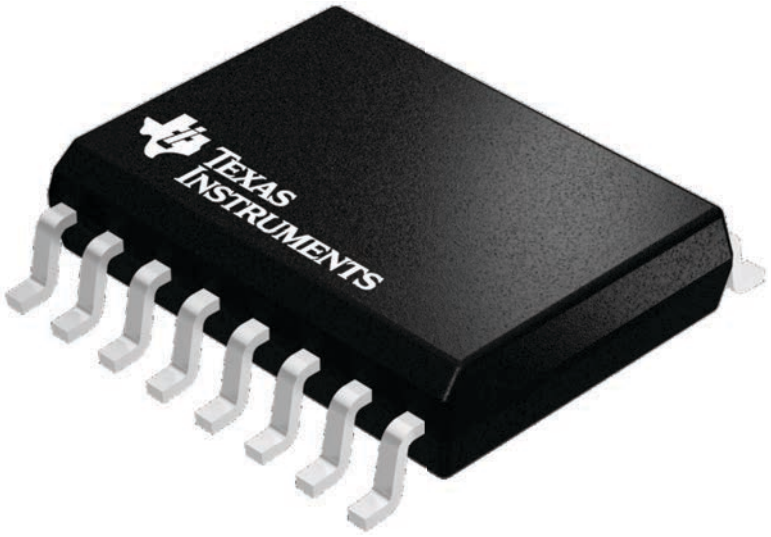
DW 16

SOIC - 2.65 mm max height

7.5 x 10.3, 1.27 mm pitch

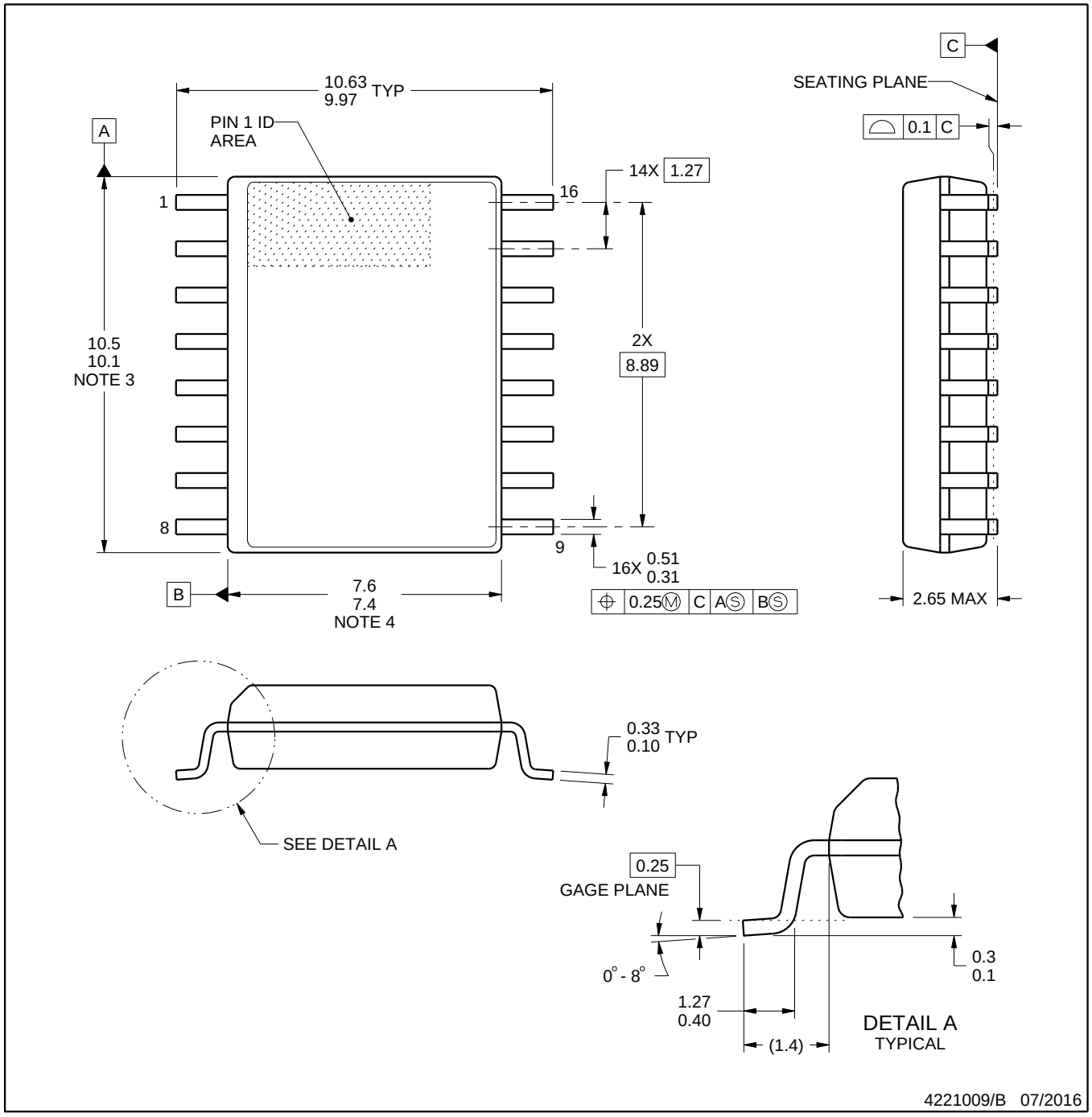
SMALL OUTLINE INTEGRATED CIRCUIT

This image is a representation of the package family, actual package may vary.
Refer to the product data sheet for package details.



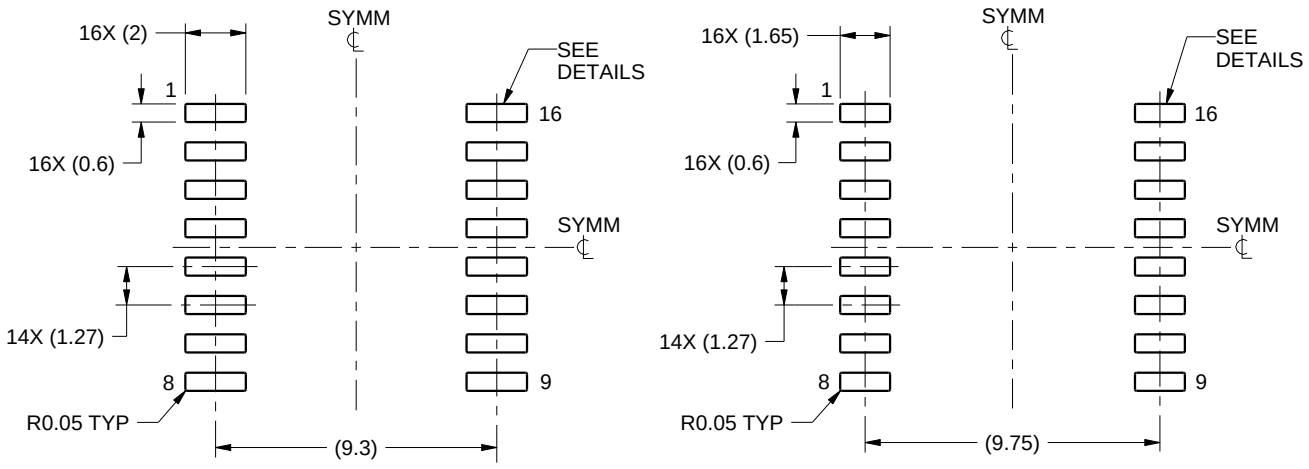
4224780/A

SOIC



NOTES:

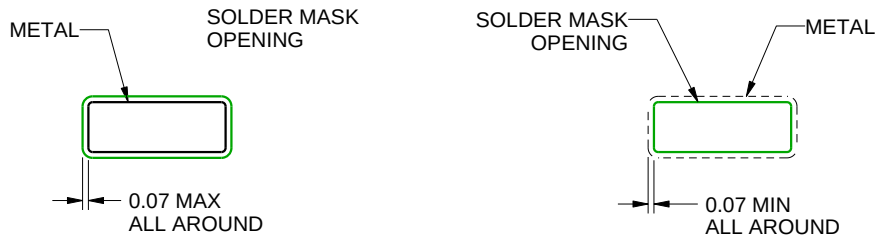
1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm, per side.
5. Reference JEDEC registration MS-013.



IPC-7351 NOMINAL
7.3 mm CLEARANCE/CREEPAGE

HV / ISOLATION OPTION
8.1 mm CLEARANCE/CREEPAGE

LAND PATTERN EXAMPLE
SCALE:4X



NON SOLDER MASK DEFINED

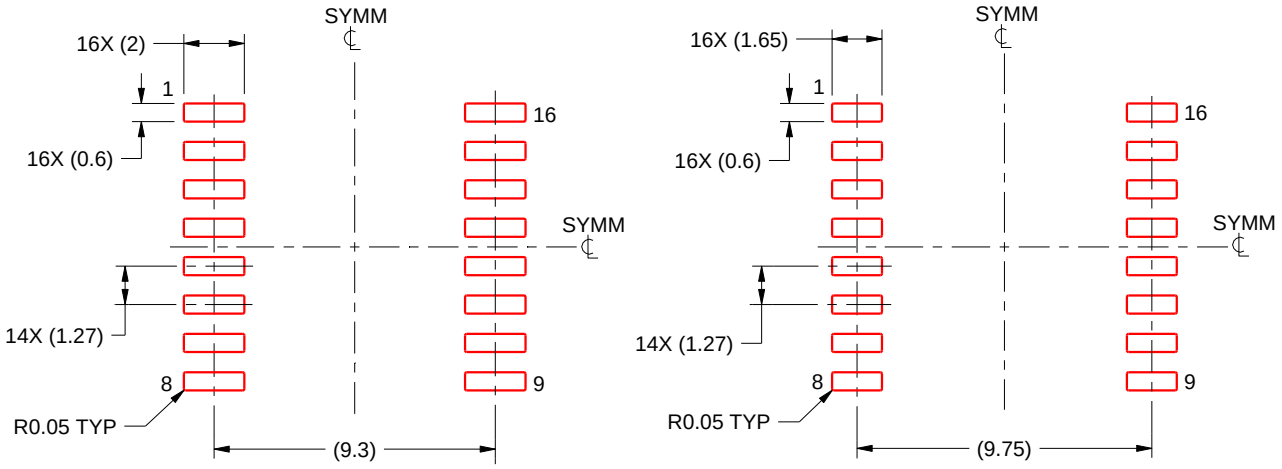
SOLDER MASK DEFINED

SOLDER MASK DETAILS

4221009/B 07/2016

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



IPC-7351 NOMINAL
7.3 mm CLEARANCE/CREEPAGE

HV / ISOLATION OPTION
8.1 mm CLEARANCE/CREEPAGE

SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE:4X

4221009/B 07/2016

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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